

[BQ25770G](https://www.ti.com/product/BQ25770G) [SLUSFK8](https://www.ti.com/lit/pdf/SLUSFK8) – APRIL 2024

BQ25770G 40V, SMBus, 2- to 5-Cell, Narrow VDC Quasi Dual Phase Buck-Boost Battery Charge Controller for GaN HEMT With System Power Monitor and Processor Hot Monitor

1 Features

TEXAS

INSTRUMENTS

- TI patented quasi dual phase buck-boost narrow voltage DC (NVDC) charger for USB-C Extended Power Range (EPR) interface platform
	- 3.5V to 40V input range to charge 2- to 5-cell battery
	- Charge current up to 16.3A/30A based on 5mΩ/2mΩ sensing resistor
	- Input current limit up to 8.2A/16.4A based on 10mΩ/5mΩ sensing resistor
	- Support USB 2.0, USB 3.0, USB 3.1, USB-C power delivery and extended power range input current setting
	- Input Current Optimizer (ICO) to extract max input power without overloading the adapter
	- Integrated Fast Role Swap (FRS) feature following USB-PD specification
	- Seamless transition between quasi dual phase buck, buck-boost, and boost operations
	- Input current and voltage regulation (IINDPM and VINDPM) against source overload
	- Battery supplements system when adapter is fully loaded
- TI patented dual ramdom spread spectrum (DRSS) for meeting IEC-CISPR 32 EMI specification
- TI patented Pass Through Mode (PTM) for >99% efficiency and battery fast charging support
- IMVP8/IMVP9 compliant system features for Intel platform
	- Enhanced Vmin Active Protection (VAP) mode supplements battery from input capacitors during system peak power spike following latest Intel specification
	- Comprehensive PROCHOT profile
	- Two level discharge current limit PROCHOT profile to avoid battery wear out
	- System power monitor (PSYS)
- Input and battery current monitor through dedicated pins
- Integrated 16-bit ADC to monitor voltage, current and power
- Battery MOSFET ideal diode operation in supplement mode
- Power up USB port from battery (USB OTG)
	- 3V to 5V OTG
- Output current limit up to 3A based on 10mΩ sensing resistor
- 600kHz/800kHz programmable switching frequency
- SMBus host control interface for flexible system configuration
- High accuracy for the regulation and monitor
	- ±0.5% Charge voltage regulation
	- ±2% Charge current regulation
	- ±2% Input current regulation
	- \pm 2% Input/charge current monitor
- **Safety**
	- Thermal regulation and thermal shutdown
	- Input, system, battery overvoltage protection
	- Input, MOSFET, inductor overcurrent protection
- Package: 36-Pins 4.0mm × 5.0mm WQFN

2 Applications

- [Standard notebook PC](https://www.ti.com/solution/standard-notebook-pc)[,Chromebook](https://www.ti.com/solution/chromebook-woa)
- [Appliances: battery charger,](https://www.ti.com/solution/appliances-battery-charger)[Oxygen concentrator](https://www.ti.com/solution/oxygen-concentrator)

3 Description

The BQ25770G is a synchronous NVDC buck-boost battery charge controller to charge a 2- to 5-cell battery from a wide range of input sources including USB adapter, extended power range (EPR) USB-C Power Delivery (PD) sources, standard power range (SPR) USB-C Power Delivery (PD) sources and traditional adapters. The device offers a low component count, high efficiency solution for space constrained, 2- to 5-cell battery charging applications.

The NVDC configuration allows the system to be regulated based on battery voltage, but not drop below system minimum voltage. The system keeps operating even when the battery is completely discharged or removed. When load power exceeds input source rating, the battery goes into supplement mode and prevents the system from crashing.

Package Information

(1) For all available packages, see [Section 13](#page-127-0).

(2) The package size (length × width) is a nominal value and includes pins, where applicable.

During power up, the charger sets the converter to a buck, boost, or buck-boost configuration based on the input source and battery conditions. The charger seamlessly transits between the buck, boost, and buck-boost operation modes without host control. The TI patented quasi dual phase converter can interleave dual phase under high power buck mode helping thermal distribution and reduce each inductor size. At same time it only needs two boost side switching MOSFETs to save overall system area and cost due to limited power operation under boost mode.

In the absence of an input source, the BQ25770G supports the USB On-the-Go (OTG) function from a 2- to 5-cell battery to generate an adjustable 3V to 5V output on VBUS with 20mV resolution.

When only a battery powers the system and no external load is connected to the USB OTG port, the BQ25770G implements the latest Intel Vmin Active Protection (VAP) feature, in which the device charges up the VBUS voltage from the battery to store some energy in the input decoupling capacitors. During a system peak power spike, the energy stored in the input capacitors supplements the system, to prevent the system voltage from dropping below the minimum system voltage and causing a system crash.

The BQ25770G monitors adapter current, battery current, and system power. The flexibly programmable PROCHOT output goes directly to the CPU for throttling back when needed.

The latest version of the USB-C PD specification includes Fast Role Swap (FRS) to ensure power role swapping occurs in a timely fashion so that the device(s) connected to the dock can avoid experiencing momentary power loss or glitching. This device integrates FRS in compliance with the PD specification.

TI patented switching frequency dithering pattern can significantly reduce EMI noise over the whole conductive EMI frequency range (150kHz to 30MHz). Multiple dithering scale options are available and provide flexibility for different applications. The ditherring feature greatly simplify EMI noise filter design.

The charger operate in the TI patented Pass Through Mode (PTM) to improve efficiency over the full load range. In PTM, input power directly pass through the charger to the system. Switching losses of the MOSFETs and inductor core loss can be saved thus achieving high efficiency operation.

The BQ25770G is available in a 36-pin 4mm × 5mm WQFN package.

Simplified Application Diagram

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4 Device Comparison Table

5 Pin Configuration and Functions

Table 5-1. Pin Functions

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Table 5-1. Pin Functions (continued)

Table 5-1. Pin Functions (continued)

6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾

(1) Stresses beyond those listed under *Absolute Maximum Rating* may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Condition*. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

6.2 ESD Ratings

(1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
(2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

(2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

6.4 Thermal Information

(1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC Package Thermal Metrics](http://www.ti.com/lit/SPRA953) application report.

6.5 Electrical Characteristics

 $\rm{V_{VBUS_UVLOZ}\le V_{VBUS}\le V_{ACOV\ FALL}}$, $\rm{T_J}$ = -40°C to +125°C, and $\rm{T_J}$ = 25°C for typical values (unless otherwise noted)

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 $\rm{V_{VBUS_UVLOZ}\le V_{VBUS}\le V_{ACOV\ FALL}}$, $\rm{T_J}$ = -40°C to +125°C, and $\rm{T_J}$ = 25°C for typical values (unless otherwise noted)

6.6 Timing Requirements

6.7 Typical Characteristics BQ25770G

 R_{AC} = 10 m Ω , R_{SR} = 5 m Ω , Inductance = 3.3 µH, CCM Frequency = 600 kHz

6.7 Typical Characteristics BQ25770G (continued)

7 Detailed Description

7.1 Overview

The BQ25770G is a Narrow VDC buck-boost charger controller for portable electronics such as notebook, detachable, ultrabook, tablet, and other mobile devices with rechargeable batteries. It provides seamless transition between different converter operation modes (buck, boost, or buck-boost), fast transient response, and high light load efficiency.

The BQ25570G supports a wide range of power sources, including USB-C PD EPR ports, legacy USB ports, traditional AC-DC adapters, and so forth. It takes input voltage from 3.5 V to 40 V and charges a battery of 2 to 5-cell in series. In the absence of an input source, the BQ25770G supports the USB On-the-Go (OTG) function from a cell battery to generate an adjustable 3 V to 5 V at the USB port with 20-mV resolution.

The BQ25770G features Dynamic Power Management (DPM) to limit input power and avoid AC adapter overloading. During battery charging, as system power increases, charging current is reduced to maintain total input current below adapter rating. If system power demand temporarily exceeds adapter rating, the BQ25770G supports the NVDC architecture to allow battery discharge energy to supplement system power.

The BQ25770G monitors adapter current, battery current, and system power. The flexibility of the programmable PROCHOT output goes directly to the CPU for throttling back when needed.

The latest version of the USB-C PD specification includes Fast Role Swap (FRS) to ensure power role swapping occurs in a timely fashion so that the device(s) connected to the dock never experience momentary power loss or glitching. The device integrates FRS with compliance to the USB-C PD specification.

The TI patented switching frequency dithering pattern can significantly reduce EMI noise over the entire conductive EMI frequency range (150 kHz to 30 Mhz). Multiple dithering scale options are available to provide flexibility for different applications to simplify EMI noise filter design.

In order to be compliant with Intel IMVP8 / IMVP9, the BQ25770G includes a PSYS function to monitor the total platform power from the adapter and battery. Besides PSYS, it provides both an independent input current buffer (IADPT) and a battery current buffer (IBAT) with highly accurate current sense amplifiers. If the platform power exceeds the available power from the adapter and battery, a PROCHOT signal is asserted to the CPU so that the CPU optimizes its performance to the power available to the system.

The host controls input current, charge current, and charge voltage registers with high resolution, high accuracy regulation limits. It also sets the PROCHOT timing and threshold profile to meet system requirements.

7.2 Functional Block Diagram

7.3 Feature Description

7.3.1 Power-Up Sequence

The device powers up from the higher voltage of VBUS or VBAT through internal power selector. The charger starts up when VBUS exceeds V_{VBUS} _{UVLOZ} or VBAT exceeds V_{VBAT UVLOZ} for 5ms. Upon POR(power on reset) the charger resets all the registers to the default state. Another 5 ms later, the user registers become accessible to the host. When VBAT> VBAT_UVLO: if VBUS falls below VBUS_UVLO then adapter removal is detected to enter battery only low power mode. When VBAT< VBAT_UVLO: if VBUS falls below VBUS_UVLO then device is off without I2C communication and device will POR when VBUS rise above VBUS_UVLOZ.

Power up sequence when the charger is powered up from VBUS:

- After VBUS rises above V_{VBUS} UVLOZ, there is 50ms deglitch time. After this 50ms deglitch time, charger enables REGN_A/B LDOs. CHRG_OK pin goes high and STAT_AC is set to 1b once REGN_A/B voltages ramp up. (If EN_LWPWR set to 0b then device will be in performance mode, REGN A/B will be kept on there is a battery present before VBUS is plugged in)
- MODE pin detection is executed after device POR to determine converter topology, converter compensation option and converter switching frequency.
- VBUS qualification is then executed. During VBUS qualification process, there is a internal 20mA current sink 100ms pulse adding on VBUS pin to make sure the input source is strong enough to pass qualification. During this 100ms if V_{VBUS} _{CONVEN}<VBUS <V_{ACOV} RISE, then charger passes VBUS qualification and proceeds to the next step. However, if $V_{VBUS-UVLOZ} < VBUS < V_{VBUS-CONVEN}$ or VBUS> $V_{ACOV-RISE}$ then charger fails VBUS qualification, the charger will re-qualify VBUS every 2 s. During this 2 s, even if VBUS rise up higher than $V_{VBIJS-CONVFN}$ the converter is still shutting down due to failing VBUS qualification at the beginning.
- During VBUS qualification, Battery cell configuration is read at CELL_BATPRES pin voltage and compared to REGN A/B to determine cell configuration. The default value of CHARGE_VOLTAGE(), CHARGE_CURRENT(),VRECHG(), VSYS_MIN() and SYSOVP thresholds are loaded respectively. Also IINDPM is detected at ILIM_HIZ pin steady state voltage.
- After passing the qualification, VBUS ADC is executed one time to read the no-load VBUS voltage and save the value into ADC_VBUS() register.
- Check voltage between VBUS and ACP_A (VBUS-ACP_A) is below V_{SC} vBUSACP_FALLING to make sure eFuse or PFETs are fully turned on. If not, hold on converter power up until SC_VBUSACP is not triggered.
- Normally 226 ms after VBUS above $V_{VBIIS, CONVEN}$, converter powers up. If SC_VBUSACP keeps triggered then converter power up could wait until it is cleared.

Power up sequence when the charger is powered up from VBAT:

- If only battery is present and the voltage is above $V_{VBAT-UVLOZ}$, charger wakes up and the BATFET is turned on and connecting the battery to system.
- MODE pin detection is executed right after device POR to determine converter topology, converter compensation option and converter switching frequency.
- By default, the charger is in low power mode (EN_LWPWR = 1b) with lowest quiescent current. The REGN A/B LDO is turned off by default but when EN_LWPWR=1, the LDO is turned on, the LDO current limit is reduced to 5mA in order to minimize the quiescent current.
- The adapter present comparator is activated, to monitor the VBUS voltage.
- SDA and SDL lines stand by waiting for host commands.
- Device can move to performance mode by configuring EN_LWPWR = 0b. The host can enable IBAT buffer through setting EN_IBAT=1b to monitor discharge current. The PSYS also can be enabled by the host. CELL_BATPRES pin detection is executed one time when CELL_BATPRES pin is pulled up or REGN_A/B rise up from GND to steady state value. Note under battery only low power mode, CELL_BATPRES detection is not executed.
- In performance mode, the REGN A/B LDO is always available to provide an accurate reference and gate drive voltage for the converter.

7.3.2 MODE Pin Detection

Fixed pull down resistor is needed on MODE pin for charger multi-function programming. Refer to Table 7-1for typical resistance corresponding to each programming code. Both E96(±1%) and E48 (±2%) tolerance resistors can be used here. The two programming items are:

- Compensation Adjustment : The device can support both normal compensation and slower bandwidth compensation under extreme application scenario. When input VBUS effective capacitance is higher than 10uF, recommend to adopt "normal" option to get best transient performance; when input VBUS capacitance is lower than 10uF, recommend to adopt "slow" option to ensure converter operation stability.
- Switching frequency: The device supports both 600kHz and 800kHz switching frequency. Based on MODE pin detection, PWM_FREQ bit will be programmed accordingly.

7.3.3 REGN Regulator (REGN LDO)

The REGN LDO regulator provides a regulated bias supply for the IC and external pull up. Additionally, REGN voltage is also used to drive the buck-boost switching FETs. The pull-up rail of CELL_BATPRES pin and ILIM_HIZ pin can be connected to REGN as well. When there is no valid external 5V voltage source available on the system then REGN LDO will be powered from either the VBUS pin or VSYS pin. REGN power selector selects the lower of VBUS and VSYS if both greater than 6V; should select the higher of VBUS and VSYS is they're both lower than 6V; and should select the one higher than 6V if there is only one higher than 6V. Both REGN A and REGN B pins are connected to REGN LDO internally, no external connections between REGN_A and REGN_B are needed, however 2.2uF local decoupling capacitance are needed for both REGN_A and REGN_B pins.

When there is a qualified 5V supply in the system, it can be leveraged as a REGN source. This can reduce power loss from the internal LDO, especially when both VBUS and VSYS are much higher than 5V. The LDO can be configured to be over-driven by external 5V source. Then REGN pin will change from an analog output pin to an analog input pin. REGN_EXT bit is employed to configure in the following method.

- When there is no qualified external 5V source, host should configure REGN_EXT=0b(default status), then the internal REGN LDO regulation output voltage is 5V to normally support internal bias and switching MOSFET gate drive. There is an internal current limit to prevent LDO from over load. The current limit level is IREGN_LIM_CHARGING and it is marked as current limit 1.
- When there is dedicated qualified external 5V source(above 4.8V and below V_{REGN} ov_RISE) and REGN is the only load on external source, host should configure REGN_EXT=1b to reduce internal REGN LDO regulation output voltage to be V_{REGN_REG_EXT}(4.5V), then external 5V regulator can over drive internal LDO. Maximum500mA current limit is needed for external power supply to prevent over current damaging on internal bootstrap diode. Application diagram is referring to [Figure 7-1](#page-27-0).
- When the external 5V source (above 4.8V and below V_{REGN} ov $_{\text{RISE}}$) is also supporting other loads besides REGN, a dedicated blocking circuit is needed to prevent REGN current from sourcing into external loads before external 5V buck converter ramp up shown in [Figure 7-2](#page-27-0). Before external 5V regulator power good(PG) is active, the Q_{BLK} serves to block external loading impact on REGN A pin. After external 5V ramps up, external 5V regulation PG is active and Q_{BLK} is turned on to distribute 5V to REGN A

pin. Host should configure REGN_EXT=1b to reduce internal REGN LDO regulation output voltage to be $V_{\text{REGN REG EXT}}(4.5V)$, then external 5V regulator can over drive to internal LDO automatically.

When external 5V source is above V_{REGN_OV_RISE}, the charger should stop switching, pull down CHRG_OK pin and trigger FAULT_REGN status bit referring to [Section 7.3.26.11](#page-48-0).

Figure 7-1. External Dedicated 5-V Source Over Drive REGN

The power dissipation for driving the gates via the REGN LDO is: *PREGN = (VAC - VREGN) QG(TOT)*fSW* , where QG(TOT) is the sum of the total gate charge for all practical switching FETs (1A,1B,2A,2B,3 and 4) and *fSW* is the programmed switching frequency.

Under battery only condition, it is flexible to configure REGN on and off through below method:

- When charger is configured in low power mode(EN_LWPWR=1b), REGN by default is turned off(EN_REGN_LWPWR=0b). If customer needs REGN voltage to supply circuit, the charger enables REGN by setting EN_REGN_LWPWR=1b. In order to save quiescent current under low power mode, REGN current capability is scaled down to 5 mA typical and 3 mA minimum. When it receives host command to start up converter, like OTG or VAP mode is enabled, then REGN should automatically recover to full scale to support large gate drive current demand even with EN_LWPWR=1b.
- When charger is configured in performance mode(EN_LWPWR=0b), REGN should be turned on with full scale capability neglecting EN_REGN_LWPWR configuration. This is needed to support OTG, VAP, PSYS, IBAT, PROCHOT, and ADC features.

7.3.4 Independent Comparator Function

When CMPIN_TR pin is muxed for independent comparator input by configuring CMPIN_TR_SELECT=0b, the comparator output is low effective and the output can be latched through setting EN_CMP_LATCH =1b. Host can clear comparator output by toggling EN_CMP_LATCH bit. Comparator polarity is determined through CMP_POL bit; comparator output deglitch time is adjustable through CMP_DEG bits. With polarity HIGH (CMP_POL = 1b), there is no internal hysteresis, user can place two resistors (R_{CMP1} and R_{CMP2}) to program hysteresis externally referring to Figure 7-3. With polarity LOW (CMP_POL = 0b), the internal hysteresis is fixed at 100 mV.

CMP_POL=1b comparator hysteresis: $5V* R_{CMP1}/R_{CMP2}$ Example: $R_{\text{CMP1}} = 10k\Omega$; $R_{\text{CMP2}} = 1M\Omega$ Comparator Hysteresis is 50mV

Figure 7-3. Comparator Hysteresis External Adjustment Under CMP_POL=1b

The comparator has a dedicated force converter off protection feature which can be triggered through external system circuit. To enable this feature, set FRC_CONV_OFF=1b. Then, when the comparator output is low, the converter will be turned off, FAULT_FRC_CONV_OFF will be set to 1b, and the CHRG_OK pin will be pulled low to inform the host EC. When the comparator output returns to high, the FAULT_FRC_OFF bit is cleared and the converter resumes switching automatically. Upon adapter removal, force converter off fault should be cleared one time, if the comparator is still triggered low then the fault should be re-triggered again to keep converter disabled.

No matter CMPIN_TR pin function selection, it always has dedicated ADC channel which can be enabled though setting EN_ADC_CMPIN=1b.

Under battery only low power mode (EN_LWPWR=1b), there is a dedicated user register bit EN_LWPWR_CMP to enable independent comparator with minimum quiescent current consumption. When EN_LWPWR_CMP=1b the independent comparator is enabled.

7.3.5 Battery Charging Management

The device charges 2-cell up-to 5-cell Li-Ion batteries. The charge cycle can be fully controlled by host, or it can be autonomous (requiring no host interaction).

7.3.5.1 Autonomous Charging Cycle

When autonomous battery charging is enabled (EN_AUTO_CHG=1b, CHRG_INHIBIT=0b and CHARGE CURRENT() register is not 0 mA), the device autonomously completes a charging cycle without host involvement. The battery charging parameters can be programmed by CHARGE VOLTAGE() and CHARGE CURRENT(). The host can always control the charging operation and optimize the charging parameters by writing to the corresponding registers.

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Table 7-2. Li-Ion Charging Parameter Default Settings

An autonomous charge cycle starts when the following conditions are valid:

- Converter starts up
- Battery autonomous charge is enabled (EN_AUTO_CHG = 1b)
- CHARGE_CURRENT() register is not 0 mA
- CHRG_INHIBIT bit is not 1b
- No SYSOVP/VSYS_UVP/ACOC/TSHUT/BATOVP/BATDOC/SC_VBUSACP/Force converter off faults
- No safety timer fault

The device automatically terminates the charging cycle when the charging current is below termination threshold, charge voltage is above recharge threshold, and device is not in DPM mode. When a full battery voltage is discharged below recharge threshold (threshold selectable via VRECHG[3:0] bits), the device automatically starts a new charging cycle. After the charge is terminated automatically, changing CHRG_INHIBIT bit from 1b to 0b or CHARGE_CURRENT() from 0A to non zero value can initiate a new charging cycle.

The status register (CHRG_STAT) indicates the different charging phases as:

- 000 Not Charging
- 001 Trickle Charge (VBAT < V_{BAT} SHORT)
- 010 Pre-charge (V_{BAT_SHORT} < VBAT < VSYS_MIN() setting)
- 011 Fast-charge (CC mode)
- 100 Taper Charge (CV mode)
- 101 Reserved
- 110 Reserved
- 111 Charge Termination Done

7.3.5.2 Battery Charging Profile

The device charges the battery in four phases: trickle charge, pre-charge, constant current, constant voltage. At the beginning of a charging cycle, the device checks the battery voltage and regulates current/voltage accordingly. If autonomous charging is enabled, automatic termination can be achieved and automatic recharge will begin when VBAT drops below certain value of CHARGE_VOLTAGE(), user registers VRECHG bits are used to configure battery re-charge threshold.

When charger is in trickle charge status (VBAT<V_{BAT SHORT}) and EN_LDO=1b, charge current is upper limited by I_{BAT, SHORT} to prevent battery from overcurrent charge and wake up battery pack. The practical charge current should be the lower value of CHARGE_CURRENT() and I_{BAT SHORT} to provide EC flexibility to program trickle charge current following battery package request. Note when EN_LDO=0b, IBAT SHORT current clamp is not effective and provide EC flexibility to program charge current through CHARGE_CURRENT() register.

When charger is in pre-charge status (V_{BAT} $_{SHORT}$ <VBAT<VSYS_MIN()) and EN_LDO=1b, charge current is the lower value of IPRECHG() and CHARGE CURRENT() setting; and the maximum charge current is limited by maximum setting of IPRECHG() which is 2048mA to prevent overheat generated on BATFET. Under this condition larger VSYS MIN() minus VBAT delta and larger charge current should generate more thermal dissipation at BATFET which should be properly limited to ensure safe operation. Therefore the device has

additional two levels current clamp to ensure the maximum BATFET dissipation loss below 2W based on the relationship between VBAT and VSYS MIN() setting referring to [Table 7-9](#page-47-0). Note when EN_LDO=0b, precharge current limit (IPRECHG()) is not effective and provide EC flexibility to program charge current through CHARGE_CURRENT() register.

If the charger device is in DPM regulation during charging, the actual charging current will be less than the programmed value. In this case, termination is temporarily disabled and the charging safety timer is counted at half the clock rate, as detailed in Charging Safety Timer section.

Figure 7-4. Typical Li-Ion Battery Charging Profile

7.3.5.3 Charging Termination

When autonomous charging is not enabled (EN_AUTO_CHG=0b), the battery charging termination be can be executed when host write CHARGE_CURRENT() register to 0A or set CHRG_INHIBIT=1b based on battery gauge device request.

When autonomous charging is enabled (EN AUTO CHG=1b), the device terminates a charge cycle when the battery voltage is above the recharge threshold, the converter is operated in the battery constant voltage regulation loop and the current is below the termination current threshold (ITERM() register setting). After the charging cycle is completed, the CHARGE_CURRENT() register is set to 0A to terminate charge and BATFET turns off. The original CHARGE_CURRENT() register setting is logged internally and resumes it to

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CHARGE_CURRENT() when re-charge condition is detected to restart charging. The converter keeps running to power the system and the BATFET can turn on again if the supplement mode is triggered.

When termination is done, the status register CHRG_STAT is set to 111b. The charger can be configured to pull down CHRG_OK pin for minimum 256 μs to inform host that charging is terminated when CHRG_OK_INT bit is set to 1b. Termination is temporarily disabled when the charger device is in input current (IINDPM), input voltage (VINDPM) or TREG thermal regulation. The deglitch times for determining IINDPM active and VINDPM active is 1 ms, and deglitch times for determining TREG active is 10 ms.

7.3.5.4 Charging Safety Timer

The device has a built-in fast charge safety timer to prevent extended charging cycle due to abnormal battery conditions. The user can program fast charge safety timer through CHG TMR register bits. When safety timer expires, charging should stop through setting CHARGE CURRENT() to 0A. The status register CHG_TMR_STAT bit is set to 1 and CHRG_STAT bits will be set to 000b(not charging), and CHRG_OK pin can be configured to be pulled low for minimum 256us to inform host if CHRG_OK_INT=1b. CHG_TMR_STAT bit will keep its 1b status until safety timer gets reset. The safety timer feature can be disabled by clearing EN_CHG_TMR bit.

During IINDPM and VINDPM regulation, or TREG thermal regulation, the safety timer counts at half clock rate as the actual charge current is likely to be below the programmed setting. For example, if the charger is in input current regulation throughout the whole charging cycle, and the safety timer is set to 5 hours, then the timer will expire in 10 hours. This half clock rate feature can be disabled by setting EN_TMR2X = 0. Changing the EN_TMR2X bit while the device is running has no effect on the safety timer count, other than forcing the timer to count at half the rate under the conditions dictated above. The deglitch times for determining IINDPM active and VINDPM active is 1ms, and deglitch times for determining TREG active is 10ms.

During faults which disable charging, timer is suspended. Since the timer is not counting in this state, the EN_TMR2X bit has no effect. Once the fault goes away, safety timer resumes. If the charging cycle is stopped and started again, the timer gets reset (toggle CHRG_INHIBIT bit restarts the timer, change CHARGE_CURRENT() register from non zero to zero and then non zero, charged battery falls below recharge threshold after termination).

The safety timer is reset for the following events:

- 1. Charging cycle stop and restart (toggle CHRG_INHIBIT bit, or charge-terminated battery falls below recharge threshold after termination, or change CHARGE_CURRENT() register from zero and then non zero)
- 2. BAT voltage changes from pre-charge to fast-charge or vice versa
- 3. Safety Timer (CHG_TMR[1:0]) register bits are changed
- 4. Toggle EN_CHG_TMR bit, when EN_CHG_TMR becomes 0b, the safety timer should be reset and count from beginning when re-enable again(EN_CHG_TMR=1b)

The pre-charge safety timer (fixed 2hr counter that runs when VBAT < VSYS_MIN()), follows the same rules as the fast-charge safety timer in terms of getting suspended, reset, and counting at half-rate when EN_TMR2X is set. Note pre-charge safety timer applies to both pre-charge and trickle charge phase.

7.3.6 Temperature Regulation (TREG)

In high power application, monitoring and controlling external component temperature can enhance reliability by limiting the total converter power under certain scenarios. The CMPIN_TR pin can be configured as temperature regulation feedback sensing pin when CMPIN_TR_SELECT=1b. It is the temperature feedback pin temperature regulation loop. The external voltage divider circuit is shown in Figure $7-5$ consisting of R_S and NTC resistor R_{TH} . External NTC is placed where temperature is regulated (for example charger power stage) and generates feedback voltage on CMPIN_TR pin based on temperature variation. When temperature is lower than target, the voltage should be above 1.2 V, temperature regulation is not effective and TREG_STAT=0b ; As temperature increases, CMPIN_TR pin voltage drops to $V_{TREG}=1.2$ V or lower, converter begin to reduce converter current and regulate CMPIN_TR voltage to stay at 1.2 V and set TREG_STAT=1b which is locked until host read or REG_RESET bit action.

To enable temperature regulation feature:

- Set CMPIN_TR_SELECT=1b to configure CMPIN_TR_SELECT pin as temperature regulation feedback pin.
- Make sure AC is plugged in and charge is enabled CHARGE_CURRENT() is non-zero and CHRG_INHIBIT=0b).
- Set EN_TREG=1b to enable temperature regulation and pull CMPOUT pin to GND.

The R_S and NTC resistor R_{TH} network generate some quiescent current which may not be negligible under light load. In order to reduce quiescent current under light load, instead of pull down R_{TH} to GND locally at power stage, we can pull down through CMPOUT pin shown in Figure 7-5. Under either TREG is enabled (CMPIN TR SELECT=1b & EN TREG=1b) or thermal PROCHOT channel is enabled (CMPIN_TR_SELECT=1b & PP_THERMAL=1b), then CMPOUT pin is pulled down to GND to generate sensing voltage on CMPIN_TR pin. However under light load both TREG and PP_THERMAL can be both disabled (CMPIN_TR_SELECT=1b & EN_TREG=0b & PP_THERMAL=0b), then device will keep CMPOUT pin high impedance to reduce quiescent current flow through voltage divider network.

Figure 7-5. Recommended Configuration for CMPIN_TR Temperature Regulation

The target temperature regulation value can be chosen through configuring R_S fixed resistor. A 10k NTC thermistor(ERTJ0EG103FA) is recommended in this application, corresponding R_S fixed value can be calculated through equation below. The R_S corresponding value at $60^{\circ}C/80^{\circ}C/100^{\circ}C$ TREG refers to Table 7-4. The corresponding CMPIN_TR pin voltage with swept temperature under 60°C/80°C/100°C TREG configuration can be found in [Figure 7-6](#page-33-0). Based on this graph, besides temperature regulation function, the NTC temperature can also be measured through CMPIN_TR pin voltage. The device has a dedicated CMPIN_TR pin voltage ADC channel which can be enabled through setting EN_ADC_CMPIN=1b.

There is a dedicated PROCHOT profile in case regulation target gets overheat more than TREG target. The profile can enabled through setting PP_THERMAL=1b referring to [Figure 7-10.](#page-44-0)

$$
R_S = \frac{5V - 1.2V}{1.2V} * R_{NTC} \omega TREG \tag{1}
$$

Table 7-4. CMPIN_TR Pin RC Network Configuration Reference Based on ERTJ0EG103FA NTC

7.3.7 Vmin Active Protection (VAP) When Battery Only Mode

When only battery is connected and adapter is removed, the system peak power pulse for a 2S or 3S system can be very high if the SoC and motherboard systems spikes coincide. These spikes are expected to be very rare, but possible. During these high power spikes, VSYS voltage could drop lower than minimum system voltage and crash the system considering the impedance of BATFET, charge sensing resistor and battery pack internal resistance. In VAP mode the charger first charges up the voltage of the input decoupling capacitors at VBUS to store a certain amount of energy. During these high system power spikes, the the energy stored in the input capacitors will supplement the system, to prevent the system voltage from dropping below the minimum system voltage and leading the system to black screen. The VAP mode can help to achieve much better Turbo performance for Intel CPU. Overall VAP mode is both a protection mechanism used to keep the system voltage from drooping below its minimum operational voltage and a method to boost Turbo performance by allowing Intel CPU to set a peak power higher than the capability of the battery.

Figure 7-7. Vmin Active Protection (VAP) Mode Operation Diagram

To enter VAP mode follow the steps below:

- Set VAP input capacitor voltage regulation target in OTG VOLTAGE().
- Set VAP mode loading current in OTG CURRENT().
- Set VSYS TH1 as the VSYS threshold to begin VAP shooting.
- Set VSYS TH2 as the VSYS threshold to trigger PROCHOT.
- Set VBUS VAP TH as the VBUS threshold to trigger PROCHOT.
- Set OTG_VAP_MODE=0b to use EN_OTG pin to enabled/disable VAP mode.
- Remove adapter and pull up EN_OTG pin to enter VAP mode.

When an adapter is plugged in or CPU goes to sleep mode, the host can follow below steps to exit VAP mode:

- Pull down EN_OTG pin to disable VAP mode
- Set OTG_VAP_MODE=1b to use EN_OTG pin to enable/disable OTG mode.

EN OTG pin is used as multi-function pin to enable OTG, VAP and FRS mode. In order to enter VAP mode correctly, refer to [Table 7-5](#page-35-0) case 7 for reference, note OTG_VAP_MODE=0b should be configured before EN_OTG pin is pulled high. After EN_OTG pin is pulled up, it is not recommended to change OTG_VAP_MODE bit value.

7.3.8 Two Level Battery Discharge Current Limit

To prevent the triggering of battery overcurrent protection and avoid battery wear-out, two battery current limit levels (IDCHG_TH1 and IDCHG_TH2) PROCHOT profiles are recommended. Define IDCHG_TH1 through REG0x34h[15:10], IDCHG TH2 is set through REG0x36[5:3] for fixed percentage of IDCHG TH1. There are dedicated deglitch time setting registers (IDCHG DEG1 and IDCHG DEG2) for both IDCHG TH1 and IDCHG_TH2.

• When battery discharge current is continuously higher than IDCHG TH1 for more than IDCHG DEG1 deglitch time, PROCHOT is asserted immediately. If the discharge current reduces to lower than IDCHG_TH1, then the IDCHG_DEG1 deglitch time counter resets automatically. STAT_IDCHG1 bit will be set to 1 after PROCHOT is triggered.

Setting PP_IDCHG1=1b to enable IDCHG_TH1 for triggering PROCHOT.

• When battery discharge current is continuously higher than IDCHG_TH2 for more than IDCHG_DEG2 deglitch time, PROCHOT is asserted immediately. If the discharge current reduces to lower than IDCHG_TH2, then the IDCHG_DEG2 deglitch time counter resets automatically. STAT_IDCHG2 bit will be set to 1 after PROCHOT is triggered.

Setting PP_IDCHG2=1b to enable IDCHG_TH2 for triggering PROCHOT.

Figure 7-8. Two Level Battery Discharging Current Trigger PROCHOT Diagram

7.3.9 Fast Role Swap Feature

Fast Role Swap (FRS) means charger quickly swaps from power sink role to power source role to provide an OTG output voltage to accessories when the original power source is disconnected. This feature is defined to transfer the charger from forward mode to OTG mode quickly without dropping VBUS voltage per USB-C PD specification requirement.

To enable FRS feature, EN_FRS bit should be set to 1. When FRS is enabled (EN_FRS = 1), EN_OTG bit and converter OTG mode is only enabled after hardware EN_OTG pin is pulled up. Note when EN_FRS is reset to 0, EN OTG bit will not be reset automatically, in order to fully exit the OTG mode operation EN OTG bit need to be reset by the host. The steps for FRS feature operation are listed below.

- Set target IOTG current limit in OTG CURRENT()
- Set target VOTG voltage in OTG VOLTAGE()
- Set OTG_VAP_MODE = 1
- Enable FRS feature by setting EN_FRS = 1.
- Remove adapter and VBUS begin to drop
- USB Type-C port PD controller should pull up EN_OTG pin to enable OTG mode. If VBUS>VOTG at the beginning, the converter shuts down and waits for VBUS dropping to VOTG; as long as VBUS≤VOTG, the converter resumes switching and VOTG (CV/CC) loop takes over.

The table below compares VAP, OTG and FRS feature configuration. It is recommended to configure charger into target mode correctly before the EN_OTG pin is pulled up. After the EN_OTG pin is pulled up, it is not recommended to change the OTG VAP MODE and EN_FRS bits.

	CONFIGURATION					
CASE#	EN_OTG PIN	OTG_VAP_MOD E BIT	EN_OTG BIT	EN_FRS BIT	BATTERY/ ADAPTER CONFIG	CHARGER STATUS
	0	X	X	X	Battery only	Battery only Discharge and converter off
\mathfrak{p}	Ω	0	X	X	Adapter+Battery	Forward mode (without FRS)
3	0		X	0	Adapter+Battery	Forward mode (without FRS)
4	0		X		Adapter+Battery	Forward mode (with FRS standby)
5			Ω	X	Battery only	Battery only Discharge and converter off
6				X	Battery only	OTG mode

Table 7-5. VAP /OTG /FRS Configuration Comparison

Table 7-5. VAP /OTG /FRS Configuration Comparison (continued)

7.3.10 CHRG_OK Indicator

CHRG OK is an active high open drain indicator. Under forward mode when VBUS is above V_{VBUS} CONVEN then CHRG_OK pin behavior is summarized below:

- Under non-latched faults ACOV/ACOC/TSHUT/BATOVP (only when charge is enabled)/BATDOC/ REGN_PG/force converter off, CHRG_OK will be pulled down for minimum pulse 256 μs. Even the fault is removed before 256 μs expire, the CHRG_OK pin should still be pulled down until 256 μs timer expires. When 256 us timer expires, if the fault still exists then the CHRG_OK pin should be kept low.
- Under latched faults SYSOVP/VSYS_UVP, CHRG_OK will be pulled down and latched until EC write 0b to FAULT_SYSOVP/FAULT_VSYS_UVP bits.
- CHRG OK pin can be also configured as interrupt source to inform host about the CHRG STAT bits changes. To enable this, host needs to set CHRG_OK_INT bit to be 1b, then whenever there is a change in CHRG_STAT bits, CHRG_OK pin will be pulled down for 256 μs to inform the host. Note: safety timer changes the CHRG STAT status as well when triggered, therefore when CHRG OK INT bit is set 1b, CHRG_OK pin is pulled down for 256 μs when safety timer triggers.

Under battery only OTG mode, if OTG ON CHRGOK=1b, the CHRG OK pin should be low when converter shuts off due to faults SYSOVP/VSYS_UVP/OTG_UVP/OTG_OVP/TSHUT/BATDOC/REGN_PG/force converter off; if OTG_ON_CHRGOK=0b, the CHRG_OK pin should be always be pulled down.

7.3.11 Input and Charge Current Sensing

The charger supports 10 mΩ and 5 mΩ for input current sensing . By default 10 mΩ is enabled by POR setting RSNS RAC=0b. If 5-mΩ sensing is used, configure RSNS RAC=1b. Lower current sensing resistor can help improve overall charge efficiency especially under heavy load. At same time, PSYS/IADPT pin accuracy and IINDPM/IOTG regulation accuracy get worse due to effective signal reduction in comparison to error signal components.

The charger supports 5 m Ω and 2 m Ω for charge current sensing . By default 5 m Ω is enabled by POR setting RSNS RSR=0b. If 2-mΩ sensing is used, configure RSNS RSR=1b. Lower current sensing resistor can help improve overall charge efficiency especially under heavy load. At same time, PSYS/IBAT pin accuracy and ICHG/IPRECHG regulation accuracy is reduced due to effective signal reduction in comparison to error signal components.

When RSNS_RAC=RSNS_RSR=0b, 10 mΩ is used for input current sensing and 5 mΩ is used for charge current sensing, the pre-charge current upper limit is clamped at 2016 mA through IPRECHG() register, the maximum IIN HOST setting is clamped at 8.2 A, and the maximum charge current is clamped at 16.32 A.

When RSNS_RAC=RSNS_RSR=1b, 5 mΩ is used for input current sensing and 2 mΩ is used for charge current sensing, the maximum IIN_HOST setting is clamped at 16.4 A. The maximum charge current is clamped at 30 A (with 20 mA LSB , 5DCh for CHARGE_CURRENT[13:3]). System note: Under 2-mΩ charge resistor, the pre-charge current upper limit is compensated and still clamped at 2040 mA through IPRECHG() register (66H). However I_{BAT} s_{HORT} does not need to be compensated should increase from 128 mA (RSR=5 mΩ) to 320 mA(RSR=2 m $\overline{\Omega}$).

If PSYS function is needed, practical input current sensing and charge current sensing should be consistent with RSNS_RSR and RSNS_RAC configuration. This is necessary because of the PSYS calculation method referring to [Equation 2.](#page-40-0)

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7.3.12 Input Current and Voltage Limit Setup

The actual input current limit being adopted by the device is the lower value of IIN_DPM and ILIM_HIZ pin. Register IIN_DPM input current limit value will be updated on below scenarios:

- IIN DPM() will be updated based on IIN HOST() value except ICO is executed listed below.
- When adapter is removed, IIN_HOST will be reset to 5 A, host can re-write IIN_HOST to new values after reset under battery only. If the adapter plugs back in and CHRG_OK is pulled up, IIN_HOST will not be reset again. IIN_DPM follows IIN_HOST value in this scenario.
- When input current optimization (ICO) is executed (EN_ICO_MODE=1b), the charger will automatically detect the optimized input current limit based on adapter output characteristic. The final IIN_DPM register setting could be different from IIN_HOST after ICO.

The input current limit function is enabled by default through (EN_IIN_DPM=1b), it can be disabled through setting EN_IIN_DPM=0b. Status bit IN_IIN_DPM is used to report input current under IIN_DPM() regulation.

The input voltage limit is configurable through VINDPM() register bits. Upon POR, VINDPM() default setting is A0h (3.2 V). EC host can rewrite to the target value after POR. There is also DETECT_VINDPM bit to DETECT VINDPM based on VBUS measurement result minus 1.28 V. Write 1b to DETECT_VINDPM bit to start the process, then converter shuts off to measure VBUS. After VBUS measurement is done, VINDPM() is written with value VBUS-1.28 V, DETECT_VINDPM bit goes back to 0 and converter starts up again. Status bit IN_VINDPM is used to report input voltage is under VINDPM regulation.

7.3.13 Battery Cell Configuration

CELL_BATPRES pin is biased with a resistor divider from REGN_A/B to GND. After REGN_A/B ramps up or CELL_BATPRES pin ramps up, the device detects the battery configuration through CELL_BATPRES pin bias voltage after 2ms delay time. No external cap is allowed at CELL_BATPRES pin. When CELL_BATPRES pin is pulled down to GND at the beginning of device start up process, CHARGE_VOLTAGE(), SYSOVP, VSYS_MIN() and VRECHG() follow battery removal row in the table below.

After device start up when battery is removed, CELL_BATPRES pin should be pulled low through external MOSFET shown in application diagram. If CELL_BATPRES pin is pulled lower than VCELL BATPRES FALL for 1ms deglitch time, then device disables charge by resetting CHARGE_CURRENT()=000h and EN_AUTO_CHG=0b; at same time, CHARGE VOLTAGE(), SYSOVP, VSYS MIN() and VRECHG() are not changed. When REGN_A/B voltage rises up or CELL_BATPRES pin is increased higher than V_{CELL_BATPRES_RISE}, the device should re-read cell configuration again with 2ms delay time: CHARGE_VOLTAGE(), SYSOVP, VSYS_MIN() and VRECHG() should be re-detected to corresponding cell setting default value if they are not changed by EC before; if any of CHARGE_VOLTAGE(), SYSOVP, VSYS_MIN() and VRECHG() are changed by EC before this re-detection then their value should not be influenced by the new detection process anymore. This is needed to avoid EC writing target value back and forth. Refer to Table 7-6 for CELL_BATPRES pin configuration typical voltage for swept cell count. Note if device is in learn mode (EN_LEARN=1b). Pulling CELL_BATPRES pin low clears EN_LEARN bit to 0b and forces device to exit learn mode.

When CELL_BATPRES pin is pulled to ground, battery removal is indicated. Since there is no battery supplement, the charger can automatically disable IIN_DPM by setting EN_IIN_DPM to 0 to minimize VSYS voltage drop. This function can be enabled through setting IIN DPM AUTO DISABLE=1b. The host can reenable IIN_DPM function later by writing EN_IIN_DPM bit to 1.

Table 7-6. Battery Cell Configuration

7.3.14 Device HIZ State

When input source is present, the charger enters HIZ mode when ILIM_HIZ pin voltage is below 0.4 V or EN HIZ is set to 1b. During HIZ mode converter shuts off and BATFET is turned on to supplement system from battery if BATFETOFF HIZ=0b. The BATFET can also be turned off during HIZ mode through setting BATFETOFF_HIZ=1b. In order to exit HIZ mode, ILIM_HIZ pin voltage has to be higher than 0.8 V and EN_HIZ bit has to be set to 0b. Once host clears HIZ mode, converter resumes switching and BATFET is turned off again.

7.3.15 USB On-The-Go (OTG)

The device supports USB OTG operation to deliver power from the battery to other portable devices through USB port. The OTG output voltage is set in OTG_VOLTAGE() register with 20 mV LSB range from 3.0 V to 5 V. The OTG output current limit is set in OTG CURRENT() register with 50 mA LSB range from 0 A to 3 A under 10 mΩ input current sensing. Status bit IN_IIN_DPM is used to report output current is under OTG_CURRENT() regulation; status bit IN_VINDPM is used to report output voltage is under OTG_VOLTAGE() regulation. Both OTG voltage and OTG current are qualified for USB-PD programed power supply (PPS) specification in terms of resolution and accuracy. The OTG operation can be enabled if the conditions are valid:

- Set target OTG current limit in OTG CURRENT() register.
- Set target OTG voltage in OTG_VOLTAGE() register.
- VBUS is below V_{VBUS} CONVENZ.
- VBAT is higher than $\rm V_{BAT\,\,OTGEN}$ level.
- EN_OTG pin is HIGH, EN_OTG = 1b and OTG_VAP_MODE = 1b.
- 15 ms after the above conditions are valid, converter starts and VBUS ramps up to target voltage. CHRG_OK pin goes high if OTG_ON_CHRGOK= 1b.

EN_OTG pin is used as multi-function to enable OTG, VAP and FRS mode. In order to enable OTG mode correctly, please refer to [Table 7-5](#page-35-0) case 6. OTG VAP MODE=1b should be configured before EN_OTG pin pulled high. After EN_OTG pin is pulled up, it is not recommended to change OTG_VAP_MODE bit value.

7.3.16 Quasi Dual Phase Converter Operation

Converter can be configured under quasi dual phase buck boost operation through MODE pin referring to [Table](#page-26-0) [7-1](#page-26-0). The charger operates in buck, buck-boost and boost mode under different VBUS and VSYS combination. The buck-boost can operate seamlessly across the three operation modes. The 6 main switches operating status under continuous conduction mode (CCM) are listed below for reference.

- Buck mode operation: Q4 is constant on and two buck phases should both switching at frequency determined at PWM_FREQ bit. There should be 180 degree interleave between phase A and B to minimize inductor total ripple and finally reduce VBUS and VSYS voltage ripple. Supporting phase shedding feature, converter can automatically transit to phase A single phase operation under light load. The transition threshold is based on SINGLE_DUAL_TRANS_TH bits configuration.
- Buck-boost mode operation: Under quasi dual phase configuration, 2*Fsw switching frequency will be distributed between two buck phases and one boost phase. They should switch in sequence like SW1_A- >SW2->SW1_A->SW1_B->SW2-> SW1_B->SW1_A->SW2->SW1_A... equivalent frequency of each phase can be calculated by 2*Fsw/3. For example, when PWM_FREQ=1b (600 kHz), then Phase A, Phase B and boost phase leg will be switching at 400 kHz.
- Boost mode operation: Q1_A and Q1_B should be constant on and the boost half bridge keeps switching at frequency determined at PWM_FREQ bit. Due to two buck phase inductors are in parallel to reduce total inductor current ripple, under boost mode switching frequency is doubled to 2*Fsw (MODE pin configured as quasi dual phase). There could be some CCM/PFM bounce back and force under certain load range(around 2.5A~3A). This bounce will not generate negative input current at input side but could generate some charge current ripple. Once load is higher or lower than this critical range, this issue will disappear.

Table 7-7. MOSFET Operation

Table 7-7. MOSFET Operation (continued)

7.3.17 Continuous Conduction Mode (CCM)

With sufficient charge or system current, converter operates under CCM. During the dead time when both MOSFETs are off, the body-diode of the low-side power MOSFET conducts the inductor current.

During CCM, the inductor current always flows. Having the LSFET turn-on when the HSFET is off keeps the power dissipation low and allows safe charging at high currents.

7.3.18 Pulse Frequency Modulation (PFM)

In order to improve converter light-load efficiency, BQ25770G switches to PFM operation at light load. The effective switching frequency will decrease accordingly when system load decreases. The minimum frequency can be limited to 20 kHz when the OOA feature is enabled (EN_OOA=1b).

7.3.19 Switching Frequency and Dithering Feature

Normally, the IC switches in fixed frequency which can be adjusted through FSW_SYNC pin. The charger also supports frequency dithering function to improve EMI performance and help pass IEC-CISPR 32 specification. This function is disabled by default with setting EN_DITHER=00b. It can be enabled by setting EN DITHER=01/10/11b, the switching frequency is not fixed when dithering is enabled, it varies within determined range by EN_DITHER setting, 01/10/11b is corresponding to $\pm 2\%/4\%/6\%$ switching frequency. The larger dithering range is selected, the smaller EMI noise peak will be, but at same time slightly larger output capacitor voltage ripple is generated. Therefore, the dithering frequency range selection is a trade-off between EMI noise peak and output voltage ripple, recommend to choose the lowest dithering range which can pass IEC-CISPR 32 specification. The patented dithering pattern can improve EMI performance from switching frequency and up to 30-MHz high frequency range which covers the entire conductive EMI noise range.

It should be noted that the Dithering feature will not work if an external clock is provided.

7.3.20 Current and Power Monitor

7.3.20.1 High-Accuracy Current Sense Amplifier (IADPT and IBAT)

A high-accuracy current sense amplifier (CSA) is used to monitor the input current during forward charging, or output current during OTG (IADPT) and the charge/discharge current (IBAT). IADPT voltage is 20× (IADPT_GAIN=0b) or 40× (IADPT_GAIN=1b) the differential voltage across ACP_A and ACN_A plus ACP_B and ACN_B. IBAT voltage is 8× (IBAT_GAIN=0b) or 64×(IBAT_GAIN=1b) of the differential across SRP and SRN. To lower the voltage on current monitoring, a resistor divider from IADPT/IBAT output to GND can be used, and accuracy over temperature can still be achieved. Recommend the total resistance of the divider circuit should be at least 100 k Ω to prevent crashing IADPT/IBAT pin voltage.

- V_{IADPT} = 20 or 40 × ($V_{ACP-A} V_{ACN-A}+V_{ACP-B} V_{ACN-B}$) during forward mode and polarity is automatically flipped V_(IADPT) = 20 or 40 × (V_{ACN A} – V_{ACP} _A+V_{ACN} B – V_{ACP} B) during reverse OTG mode operation.
- V_{IBAT} = 8 or 64 \times (V_{SRP} V_{SRN}) during forward mode charging. Need to configure EN_IBAT=1b and EN_ICHG_IDCHG=1b.
- V_{IBAT} = 8 or 64 × (V_{SRN} V_{SRP}) during forward supplement mode, reverse OTG mode and battery only discharge scenario. Need to configure EN_IBAT=1b and EN_ICHG_IDCHG=0b.

A maximum 100-pF capacitor is recommended to connect on the output for decoupling high-frequency noise. An additional RC filter is optional. Note that RC filtering has additional response delay. The IADPT and IBAT output voltages are clamped at 3.2 V.

7.3.20.2 High-Accuracy Power Sense Amplifier (PSYS)

The charger monitors total system power. During forward mode, the input adapter powers the system. During reverse OTG mode and battery only discharge scenario, the battery powers the system and VBUS output. The ratio of PSYS pin output current and total system power, K_{PSYS}, can be programmed in PSYS_RATIO register bit with default 1 μA/W. The input and charge sense resistors (RAC and RSR) are selected in RSNS_RAC bit and RSNS_RSR bit. If PSYS_CONFIG=00b then PSYS voltage can be calculated with Equation 2, where I_{IN_A}/I_{IN_B} >0 when the charger is in forward charging and $I_{IN}A/I_{IN}B$ <0 when charger is in OTG operation; where $I_{BAT} < 0$ when the battery is in charging and I_{BAT} >0 when battery is discharging.

$$
V_{PSYS} = R_{PSYS} \cdot K_{PSYS} (V_{ACP_A} \cdot I_{IN_A} + V_{ACP_B} \cdot I_{IN_B} + V_{SYS} \cdot I_{BAT})
$$
\n
$$
\tag{2}
$$

For proper PSYS functionality, RAC practical value is limited to 10 mΩ or 5 mΩ and should be consistent with RSNS_RAC register setting; RSR practical value is limited to 5 m Ω or 2 m Ω and should be consistent with RSNS_RSR register setting.

Charger can block IBAT contribution to above equation by setting PSYS_CONFIG =01b in forward mode and block IBUS contribution to above equation by setting PSYS_OTG_IDCHG=1b.

To minimize the quiescent current, the PSYS function is disabled by default PSYS_CONFIG = 11b.

Table 7-8. PSYS Configuration Table

7.3.21 Input Source Dynamic Power Management

The charger supports Dynamic Power Management (DPM). Normally, the input power source provides power for the system load and/or charging the battery. When the input current exceeds the input current setting(IIN_DPM), or the input voltage falls below the input voltage setting(VINDPM), the charger decreases the charge current to provide priority to the system load. As the system current rises, the available charge current drops accordingly towards zero. If the system load keeps increasing after the charge current drops down to zero, the system voltage starts to drop. As the system voltage drops below the battery voltage, the battery will discharge to supply the heavy system load.

7.3.22 Integrated 16-Bit ADC for Monitoring

The device includes a 16-bit ADC to monitor critical system information based on the device's modes of operation. The control of the ADC is done through the ADCOption register. There are total 7 ADC channels can be enabled independently through ADCOption registers [7:0] bits. The ADC_RATE bit is used to select between continuous conversion and one-shot conversion. When continuous conversion is chosen, each enabled ADC channel will be executed one by one and continuously, the ADC cycling refresh time can be calculated by the product of enabled ADC channel count(ADCOption registers [7:0] setting) and the ADC_SAMPLE configuration (24ms/12ms/6ms). When one-shot conversion is selected, ADC_EN is used to start one-shot conversion, after a 1-shot conversion finishes, the ADC_EN bit is cleared, and must be re-asserted to start a new conversion. When ADC is under continuous mode, then ADC_EN is used to enable continuous ADC operation. To enable each channel ADC not only ADC_EN should be configured at 1b, but also need to enable the dedicated channels

in ADCOption registers [7:0] bits. The device will immediately reset ADC_EN to 0b when all ADC channels are disabled.

The ADC is allowed to operate if either the VBUS>V_{VBUS} CONVEN OF VBAT>V_{VBAT_UVLOZ} is valid. If no adapter is present (VBUS<V_{VBUS} _{CONVENZ}), and the VBAT is less than V_{VBAT UVLO}, the device will not perform an ADC measurement, nor update the ADC read-back values. Additionally, the device will immediately reset ADC_EN to 0b. If the charger changes mode (for example, if adapter is connected) while an ADC conversion is running, the conversion is interrupted. Once the mode change is complete, the ADC resumes conversion, starting with the channel where it was interrupted.

The ADC_SAMPLE bits control the resolution of the ADC, and also determine conversion time of t_{ADC} conv based on resolution. The total conversion time of one cycle ADC of all channels enabled can be estimated using channel counts multiplied by the corresponding t_{ADC} conv determined by ADC_SAMPLE setting. If an ADC channel is disabled by setting the corresponding bit, then the read-back value in the corresponding register will be from the last valid ADC conversion or the default POR value (all zeros if no conversions have taken place). If an ADC parameter is disabled in the middle of an ADC measurement cycle, the device will finish the conversion of that parameter, but will not convert the parameter starting the next conversion cycle. Even though no conversion takes place when all ADC measurement parameters are disabled, the ADC circuitry is active and ready to begin conversion as soon as one of the bits in ADCOption register[7:0] is set to '1'.

ADC conversion operates independently of the faults present in the device. ADC conversion will continue even after a fault has occurred (such as one that causes the power stage to be disabled), and the host must set ADC_EN to '0b' in order to disable the ADC. ADC conversion is interrupted upon adapter plug-in, and will only resume after REGN regulator is enabled from the input. ADC readings are only valid for DC states and not for transients. When host disables ADC by setting ADC_EN to 0b, the ADC stops immediately, and ADC measurement values correspond to last valid ADC reading.

If the host wants to exit continuous ADC more gracefully, it is possible to do either of the following:

- 1. Write ADC_RATE to one-shot, and the ADC will stop at the end of a complete cycle of conversions, or
- 2. Disable all ADC conversion channels, and the ADC will stop at the end of the current measurement.

When system load is powered from the battery (input source is removed, or device in HIZ mode), enabling the ADC automatically powers up REGN and increases the quiescent current. To keep the battery leakage low, it is recommended to duty cycle or completely disable the ADC.

7.3.23 Input Current Optimizer (ICO)

Even though the IINDPM and VINDPM features are useful to keep the system load running when reaching the adapter limit. However, the adapter will overheat when keeping it running at its current and voltage limit for a long period of time. Thus it is preferred to operate the adapter under its current rating is preferred.

The charger includes innovative automatic Input Current Optimizer (ICO) to maximize the power of input source with input current limit higher than 500 mA. Below is the steps to execute ICO function:

- Make sure system can power up by the adapter and battery can be charged in CC phase
- Set VINDPM() register value to slightly below the adapter voltage with full load specification
- Set IIN HOST() register value to the maximum amount of input current limit the user would like to sink on VBUS
- Disable external ILIM_HIZ by setting EN_EXTILIM=0b. When ICO is disabled, IIN_DPM register value should be the same as IIN_HOST.
- Set charge current in CHARGE_CURRENT register to design specification which should be high enough to support ICO evaluation
- Enable ICO test by setting EN_ICO_MODE=1b, and wait for approximately 2sec, and check the ICO_DONE status bit. If this bit goes to 1, ICO is completed
- After ICO_DONE=1b, read back ICO result in IIN_DPM register for current adapter. Value in IIN_HOST register is not changed by ICO. If the host sets EN_ICO_MODE bit back to zero, the IIN_DPM returns to the setting in IIN_HOST. To continue use the optimal input current limit identified by ICO, it is recommended to read IIN_DPM register after ICO is done and write this value back to IIN_HOST.

7.3.24 Two-Level Adapter Current Limit (Peak Power Mode)

Usually adapter can supply current higher than DC rating for a few milliseconds to tens of milliseconds. The charger employs two-level input current limit, or peak power mode, to fully utilize the overloading capability and minimize battery discharge during CPU turbo mode. The level 1 current limit, or I_{LIM1} , is the same as adapter DC current, set in IIN_DPM register. The level 2 overloading current, or I_{LIM2} , is set in ILIM2_VTH, as a percentage of I_{LIM1} .

When the charger detects input current surge and battery discharge due to load transient (both the adapter and battery support the system together), or when the charger detects the system voltage starts to drop below VSYS_MIN register setting due to load transient (only the adapter supports the system).The charger will first apply I_{LIM2} for T_{OVLD} (PKPWR_TOVLD_DEG register bits), and then I_{LIM1} for up to T_{MAX} – T_{OVLD} time. T_{MAX} is programmed in PKPWR_TMAX register bits. After T_{MAX} if the load is still high, another peak power cycle starts. Charging is disabled during T_{MAX} ; once T_{MAX} expires, charging continues. During T_{OVLD} if PP_INOM=1b and input current exceed 110%* I_{LIM1} , the PROCHOT pin should be pulled down after INOM_DEG deglitch time expires. The details can be found in Figure 7-9.

To prepare entering peak power follow the steps below:

- Set EN_IIN_DPM=1b to enable input current dynamic power management.
- Set EN_EXTILIM=0b to disable external current limit.
- Set register IIN_HOST based on adapter output current rating as the level 1 current limit(I_{LIM1})
- Set register bits ILIM2_VTH according to the adapter overload capability as the level 2 current limit(I_{LIM2}).
- Set register bits PKPWR_TOVLD_DEG as I_{LIM2} effective duration time for each peak power mode operation cycle based on adapter capability.
- Set register bits PKPWR_TMAX as each peak power mode operation cycling time based on adapter capability.

7.3.25 Processor Hot Indication

When CPU is running in turbo mode, the system peak power may exceed available power from adapter and battery together. The adapter current and battery discharge peak current, or system voltage drop is an indication that system power is too high. The charger processor hot function monitors these events, and PROCHOT pulse

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is asserted if the system power is too high. Once CPU receives PROCHOT pulse from charger, it slows down to reduce system power. The events monitored by the processor hot function include:

- ICRIT: adapter peak current, as 110% of I_{LIM2}
- INOM: adapter average current (110% of IIN_DPM)
- IDCHG1: battery discharge current level 1
- IDCHG2: battery discharge current level 2. Note that IDCHG2 threshold is always larger than IDCHG1 threshold, determined by IDCHG_TH2 register setting.
- VBUS VAP: VBUS threshold to trigger PROCHOT in VAP mode
- VSYS: system voltage on VSYS.
- Adapter Removal: upon adapter removal (PROCHOT pin is one time falling edge trigger when VBUS falls below V_{VBUS} _{CONVENZ} threshold and deglitch time is within 1 μs. If triggered, STAT_ADAPTER_REMOVAL bit will be set to 1b, it will be high until clear through host read or REG_RESET bit. The status bit is level trigger which means if VBUS is still below V_{VBUS} convENZ when status bit gets cleared, then the status bit should be triggered again immediately)
- Battery Removal: upon battery removal (PROCHOT pin is one time falling edge trigger when CELL_BATPRES pin voltage falls below V_{CELL} BATPRES FALL and deglitch time is within 1 μs. If triggered STAT_BATTERY_REMOVAL bit will be set to $1b$, it will be locked until clear through host read or REG_RESET bit. The status bit is also falling edge trigger which means if CELL_BATPRES pin is still below VCELL BATPRES FALL when status bit gets cleared, the status bit will still be cleared to 0b)
- CMPOUT: Independent comparator output (CMPOUT pin HIGH to LOW)
- VINDPM: VBUS lower than 83%/91%/100% of VINDPM setting. The effective threshold PROCHOT_VINDPM is determined by combination of register PROCHOT_VINDPM_80_90 bit and LOWER_PROCHOT_VINDPM bit:
	- PROCHOT_VINDPM=VINDPM register setting: LOWER_PROCHOT_VINDPM=0b;
	- PROCHOT_VINDPM=83% VINDPM register setting: LOWER_PROCHOT_VINDPM=1b;PROCHOT_VINDPM_80_90=0b;
	- PROCHOT_VINDPM=91% VINDPM register setting:
	- LOWER_PROCHOT_VINDPM=1b;PROCHOT_VINDPM_80_90=1b;
- **EXIT** VAP: Every time when the charger exits VAP mode.
- THERMAL: If enabled (PP_THERMAL=1b), then when the CMPIN_TR pin voltage is lower than $V_{TREG-PP}$ for 1s/100ms (THERMAL_DEG bit configurable) deglitch time. Then STAT_THERMAL will be latched until clear through host read or REG_RESET bit.

The thresholds of ICRIT, IDCHG1,IDCHG2,VSYS or VINDPM, and the deglitch times of ICRIT, INOM, IDCHG1, IDCHG2, or CMPOUT are programmable. Except for the PROCHOT_EXIT_VAP which is always enabled, the other triggering events can be individually enabled in ProchotOption1[7:0], PP_IDCHG2 and PP_VBUS_VAP. When any enabled event in PROCHOT profile is triggered, PROCHOT is asserted low for a single pulse with minimal width programmable in PROCHOT WIDTH register bits. At the end of the single pulse, if the PROCHOT event is still active, the pulse gets extended until the event is removed.

If the PROCHOT pulse extension mode is enabled by setting EN_PROCHOT_EXT= 1b, the PROCHOT pin will be kept as low until host writes PROCHOT CLEAR= 1b, even if the triggering event has been removed.

If the PROCHOT_VINDPM or PROCHOT_EXIT_VAP is triggered, PROCHOT pin will always stay low until the host clears it, no matter the PROCHOT is in one pulse mode or in extended mode. In order to clear PROCHOT_VINDPM, host needs to write 0 to STAT_VINDPM. In order to clear PROCHOT_EXIT_VAP, host needs to write 0 to STAT_EXIT_VAP.

7.3.25.1 PROCHOT During Low Power Mode

During low power mode (EN_LWPWR = 1), the charger offers a low power $\overline{PROCHOT}$ function with very low quiescent current consumption, which uses the independent comparator. This is commonly used to monitor the system voltage, and assert PROCHOT to CPU if the system power is too high and resulting system voltage is lower than specific threshold.

The register setting to enable PROCHOT monitoring system voltage in low power mode is listed below.

- $EN_LWPWR = 1b$ to enable charger low power mode.
- $REG0x34[7:0] = 00h$
- $REG0x30[6:4] = 000b$
- Independent comparator threshold is always 1.2 V

Set EN_LWPWR_CMP = 1b, CMP_POL=1b and PP_CMP=1b, charger monitors system voltage. Connect CMPIN to voltage proportional to system voltage. PROCHOT triggers from HIGH to LOW when comparator triggers low effective with VSYS falls below certain threshold .

Figure 7-11. PROCHOT Low Power Mode Implementation

7.3.25.2 PROCHOT Status

REG0x21[8:0] reports which event in the profile triggers PROCHOT if the corresponding bit is set to 1. The status bit can be reset back to 0 after it is read by the host, when the current PROCHOT event is not active any more.

Assume there are two PROCHOT events, event A and event B. Event A triggers PROCHOT first, but event B is also active. Both status bits will be HIGH. At the end of the 10 ms PROCHOT pulse, if any of the PROCHOT event is still active (either A or B), the PROCHOT pulse is extended.

7.3.26 Device Protection

7.3.26.1 Watchdog Timer (WD)

The charger includes watchdog timer 175s (default value and adjustable via WDTMR_ADJ) to reset some registers including:

- Reset CHARGE CURRENT() to 0 A to disable charge;
- Reset EN CHG TMR bit to 1b to re-enable CHG timer. If it is already enabled then no change.
- Reset EN_OTG bit to 0b to disable OTG operation.
- Reset ADC_EN bit 0b to disable ADC to save quiescent current.

There are four methods to reset the watchdog timer to prevent it from expiration, as long as one of them is met then watchdog timer will be reset:

- Write CHARGE_VOLTAGE() register;
- Write CHARGE CURRENT() register;
- Write WD_RST bit to 1b, this bit will automatically to back to 0b after watchdog timer is reset.
- Update a new watchdog timer value at WDTMR_ADJ bits, then the timer is reset with new value.

Write WDTMR_ADJ = 00b to disable watchdog timer. New non-zero charge current value has to be written to charge current register CHARGE_CURRENT() to resume charging after watchdog timer expires.

7.3.26.2 Input Overvoltage Protection (ACOV)

The charger support input over voltage protection which holds ACOV threshold with hysteresis. When VBUS pin voltage is higher than $V_{ACOV-RISE}$ for more than 100 μs, it is considered as adapter over voltage. CHRG_OK pin will be pulled low by the charger, and the converter shuts down. As system falls below battery voltage, BATFET will be turned on. When VBUS pin voltage falls below V_{ACOV} FALL for more than 1 ms, it is considered as adapter voltage returns back to normal voltage. CHRG_OK pin is pulled high by external pull up resistor. The converter resumes if enable conditions are valid. When ACOV is triggered, its corresponding status bit FAULT_ACOV will be set and it can be cleared by host read.

Under different input voltage 36V EPR/ 28V EPR/20V SPR/ 15V SPR, ACOV should be adjusted accordingly to meet converter MOSFETs protection requirement. ACOV_ADJ bits are used to adjust ACOV thresholds. By default charger ACOV protection is 33 V corresponding to 28V ERP application.

7.3.26.3 Input Overcurrent Protection (ACOC)

If the input current exceeds the 1.33× or 2× of ILIM2_VTH set point ACOC_TH(adjustable through ACOC_VTH), after 250us rising edge deglitch time converter stops switching because of input over current protection (ACOC). CHRG_OK pin will be pulled low by the charger when it is triggered. ACOC is a non-latch fault, if input current falls below set point, after 250 ms falling edge deglitch time converter starts switching again and CHRG_OK pin pull down will be released. ACOC is disabled by default and need to be enabled by configuring EN_ACOC=1b. When ACOC is triggered, its corresponding status bit FAULT_ACOC will be set and it can be cleared by host read.

7.3.26.4 System Overvoltage Protection (SYSOVP)

When the converter starts up, the BQ25770G reads CELL_BATPRES pin configuration and sets CHARGE_VOLTAGE() and SYSOVP threshold ($2s - 12$ V, $3s - 17$ V, $4s - 22$ V and $5s - 27V$). Set SYSOVP_MAX=1b can force SYSOVP threshold to be maximum 27V neglecting CELL_BATPRES pin setting. Before CHARGE_VOLTAGE() is written by the host, the battery configuration will follow CELL_BATPRES pin setting. When SYSOVP happens, the device shuts off the converter. FAULT_SYSOVP status bit is set to 1 and latched to 1b. CHRG_OK pin is latched low accordingly until host clear the status bit. The user can clear this status latch-off by either writing 0 to the FAULT_SYSOVP status bit or removing and plugging in the adapter again. After latch-off is cleared, the converter starts again.

During buck HS MOSFET short, SYSOVP is the critical protection to prevent next stage VR power stage from high input voltage. This is implemented through CHRG_OK pin pull down to cut off input source after SYSOVP triggered.

7.3.26.5 Battery Overvoltage Protection (BATOVP)

Battery overvoltage protection (BATOVP) can be enabled when battery is plugged in and charge is enabled in forward mode. In battery only OTG mode and charge disable forward operation this fault is neglected. The BATOVP rising threshold is 108% of regulation voltage set in CHARGE_VOLTAGE() register, and falling threshold is 106% of regulation voltage set in CHARGE_VOLTAGE() register. BATOVP protection is a non-latch fault and it is enabled by default (EN_BATOVP=1b), when BATOVP rising condition is triggered: if charge is enabled converter should shut down and CHRG OK pin is pulled down, the charger automatically recover switching after BATOVP comparator output falls; if charge is disabled this fault should be neglected, the converter should keep operating without disturbance and CHRG_OK pin is kept high. There is dedicated user status bit FAULT BATOVP to monitor its status. Once triggered FAULT BATOVP status bit will be set to 1b until host read to clear it. Note VBAT voltage used for BATOVP detection is based on SRN pin measurement. When BATOVP is triggered, 20-mA discharge current is added on VSYS pin to help discharge battery voltage. The 20-mA discharge current can be disabled by setting DIS_BATOVP_20MA=1b. BATOVP protection can be disabled through setting EN_BATOVP=0b.

7.3.26.6 Battery Charge Overcurrent Protection (BATCOC)

The charger monitors the battery charge current to provide the battery overcurrent charge protection(BATCOC) through voltage across SRP and SRN. BATCOC is disabled by default (BATCOC_CONFIG=00b) and can be enabled by configuring BATCOC_CONFIG=01b/10b/11b (50mV/75mV/100mV thresholds respectively).

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When the charge current is higher than the threshold after 1-us deglitch time, BATCOC fault is triggered, CHARGE_CURRENT() register is reset back to 0A and BATFET should be turned off accordingly. Status bit FAULT_BATCOC is set and it can only be cleared by host read after 1 second latch time. The above actions are only executed one time after triggered. During this 1 second latch time, non-zero value cannot be written into CHARGE_CURRENT(). In order to recover charging, host need to re-write non-zero CHARGE_CURRENT() register value after it triggers for 1 second. Note this protection only turns off BATFET to disable charge it should not influence BATFET supplement mode turn on state machine. Also the CHRG_OK pin is not influenced under BATCOC fault to avoid unnecessary interference to customer system.

7.3.26.7 Battery Discharge Overcurrent Protection (BATDOC)

Under battery only OTG operation, the charger monitors the battery discharge current to provide the battery over current protection (BATDOC) through voltage across SRN and SRP. BATDOC can be enabled by configuring EN BATDOC=1b. BATDOC threshold is selected either 200% of IDCHG TH2 or 300% IDCHG TH2 through BATDOC VTH bit. There is also fixed low and high clamp for BATDOC threshold. When 200% of IDCHG TH2 or 300% IDCHG_TH2 corresponding SRN-SRP voltage is below 50 mV, then BATDOC threshold will be low clamped at SRN-SRP=50 mV corresponding current; similarly if 200% of IDCHG_TH2 or 300% IDCHG_TH2 corresponding SRN-SRP voltage is above 180 mV , then BATDOC threshold will be high clamped at SRN-SRP=180 mV corresponding current.

When discharge current is higher than the threshold after 250-us deglitch time, BATDOC fault is triggered, status bit FAULT_BATDOC is set accordingly. Converter shuts down when BATDOC is asserted to disable OTG operation and reduce discharge current. BATFET status is not impacted if need to supplement power to system.

BATDOC is not a latch fault, therefore after BATDOC fault is removed, with 250 ms relax time, converter resume switching automatically. But status bit FAULT_BATDOC is only cleared by host read.

7.3.26.8 BATFET Charge Current Clamp Protection under LDO Regulation Mode

When charger LDO mode is enabled (EN_LDO=1b) and VBAT voltage falls below VSYS_MIN() during charging, the charger should regulate system output voltage fixed at VSYS_MIN() and battery charging current is regulated by BATFET gate voltage achieving LDO mode operation. Both charger pre-charge and trickle charge status are implemented through this LDO mode operation. Under both pre-charge and trickle charge there are corresponding current limit referring to [Battery Charging Profile.](#page-29-0) Under LDO mode larger VSYS_MIN() minus VBAT delta and larger charge current should generate more thermal dissipation at BATFET which should be properly limited to ensure safe operation. Therefore besides pre-charge and trickle charge current clamp mentioned above, we have additional two levels current clamp to ensure the maximum BATFET dissipation loss below 2W based on the relationship between VBAT and VSYS MIN() setting referring to Table 7-9. The lower current clamp will dominate the final maximum charge current limit considering IPRECHG() user register upper clamp, battery short trickle charge current clamp (128 mA) and two levels BATFET current clamp below.

Table 7-9. BATFET Charge Current Clamp Under LDO Mode

When charger LDO mode is disabled (EN_LDO=0b), then BATFET will be either fully on or fully off status. When charge is disabled the system voltage is regulated at $5 \vee$ (VBAT $\lt 5 \vee$) or VBAT+160 mV (VBAT>5 V); however when charge is enabled then VSYS will be regulated close to VBAT to implement target charging current and VSYS MIN regulation is not effective.

7.3.26.9 Sleep Comparator Protection Between VBUS and ACP_A (SC_VBUSACP)

Under forward mode, it is allowed to add an optional PFET or efuse between VBUS and ACP_A pin which can help shut off converter when there is dead short on Q1_A or Q1_B. Since the turn on delay on PFETs and eFuse is not fixed, sleep comparator protection is employed to ensure PFETs or eFuse is turned on when converter starts up. This sleep comparator is enabled by default (EN_SC_VBUS_ACP=1b) and can be disabled through

EN_SC_VBUS_ACP=0b. When it is enabled, charger monitors delta voltage between VBUS and ACP_A and triggers to shuts off converter if VBUS-ACP_A is larger than V_{SC} vBUSACP rising. It is non-latch fault and in order to resume switching VBUS-ACP_A has to be smaller than V_{SC} _{VBUSACP falling}. The comparator deglitch time is tsc VBUSACP DEG for both rising trigger and falling return. After protection is triggered converter shuts off and FAULT_SC_VBUSACP bit is set accordingly and can be cleared by a host read, note CHRG_OK pin is not pulled down during this fault, because the CHRG_OK pin needs to be high to turn on PFET or eFuse.

7.3.26.10 High Duty Buck Exit Comparator Protection (HDBCP)

Under HIGH_DUTY_BUCK=1b configuration, in order to prevent reverse boosting operation when VBUS is unplugged or reduced lower than VSYS, a dedicated comparator will force converter to exit high duty buck mode by forcing HIGH_DUTY_BUCK=0b. If VSYS is higher than 97.5% of VBUS, after 15-μs deglitch time the charger force HIGH_DUTY_BUCK back to 0b. As long as the comparator is triggered the charger should prevent HIGH_DUTY_BUCK bit from being set to 1b. HDBCP is an non-latch protection, if VSYS drops below 97.5% of VBUS minus hysteresis (80 mV), after 15-μs deglitch time HIGH_DUTY_BUCK bit is released and can be written to 1b to enter high duty buck operation.

7.3.26.11 REGN Power Good Protection (REGN_PG)

There is a dedicated REGN power good protection to guarantee converter switching under preferred gate drive voltage range. When REGN voltage is below V_{REGN OK FALL} or above V_{REGN OV} RISE, after 100-µs deglitch time FAULT_REGN status bit will be set from 0b to 1b, converter shuts off and CHRG_OK pin is pulled down to inform host. When REGN is re-qualified above $V_{REGN_OK_RISE}$ and below $V_{REGN_OV_FALL}$ for more than 100 µs, CHRG_OK pin should also be released and converter resume switching automatically. The FAULT_REGN status bit can be cleared after host read as long as the fault condition is removed.

7.3.26.12 System Under Voltage Lockout (VSYS_UVP) and Hiccup Mode

The charger VSYS_UVP is enabled by default (VSYS_UVP_ENZ=0b) and can be disabled by writing VSYS UVP ENZ=1b. This protection is mainly defined to protect converter from system short circuit under both startup and steady state process. VSYS pin is used to monitor the system voltage, system under voltage lockout threshold is configurable through VSYS UVP register bits (2.4 V upon POR), there is 2-ms deglitch time and the IIN_DPM is clamped to 0.5 A (VBUS<14.4V)/0.3A(VBUS>14.4V) to limit short circuit current. Detail protection process is slightly different based on whether hiccup mode is enabled:

If hiccup mode is enabled VSYS_UVP_NO_HICCUP = 0b, after 2-ms deglitch time, the charger should shut down for 500 ms.The charger will restart for 10 ms if VSYS is still lower than 2.4 V, the charger should shut down again. This hiccup mode will be tried continuously, if the charger restart is failed for 7 times in 90 second, the charger will be latched off. FAULT_VSYS_UVP bit will be set to 1 to report a system short fault and CHRG_OK pin is pulled accordingly. The charger only can be enabled again by writing FAULT_VSYS_UVP bit to 0b, then CHRG_OK pin can be released. Note as long as system voltage is below VSYS_UVP threshold, then IIN_DPM is also internally clamped to 0.5 A (VBUS<14.4V)/0.3A(VBUS>14.4V) to limit short circuit.

If hiccup mode is disabled VSYS_UVP_NO_HICCUP = 1b. After 2-ms deglitch time, the charger should shut down and latched off. FAULT_VSYS_UVP bit will be set to 1 to report a system short fault and CHRG_OK pin is pulled accordingly. The charger only can be enabled again once the host writes FAULT VSYS UVP bit to 0b, then CHRG_OK pin can be released.

7.3.26.13 OTG Mode Over Voltage Protection (OTG_OVP)

While operating in reverse direction, the device monitors the VBUS voltage. When VBUS exceeds V_{VBUS} _{OTG} OV there is 20-mA discharge current flow through VBUS pin. After VBUS exceeds V_{VBUS OTG OV} for 10-ms deglitch time, the device stops switching, and and clear EN_OTG bit to 0b and exit OTG mode. When the event is triggered, the FAULT OTG OVP read only bit is triggered and CHRG OK pin is pulled low if OTG_ON_CHRGOK=1b. The FAULT_OTG_OVP bit can be cleared through EC host read. In order to re-start OTG mode, EC host has to re-enable OTG mode by setting EN_OTG bit to 1b.

7.3.26.14 OTG Mode Under Voltage Protection (OTG_UVP)

While operating in reverse direction, the device monitors the VBUS voltage. When VBUS falls below V_{VBUS OTG UV} for 10-ms deglitch time due to overloading, the device stops switching and clear EN_OTG bit to 0b and exit OTG mode. When the event is triggered, the FAULT OTG UVP read only bit is triggered and CHRG_OK pin is pulled low if OTG_ON_CHRGOK=1b. The FAULT_OTG_UVP bit can be cleared through EC host read. In order to re-start OTG mode, EC host has to re-enable OTG mode by setting EN_OTG bit to 1b.

7.3.26.15 Thermal Shutdown (TSHUT)

The WQFN package has low thermal impedance, which provides good thermal conduction from the silicon to the ambient, to keep junction temperatures low. As added level of protection, the charger converter turns off for self-protection whenever the junction temperature reaches the 155°C. The charger stays off until the junction temperature falls below 135°C. During thermal shut down, the REGN LDO is scaled down to 35 mA and stays on. TSHUT is non-latched fault, when the temperature falls below 135°C charge can be resumed with soft start.

When thermal shut down is triggered, TSHUT status bit will be triggered. This status bit keep triggered until host read to clear it. If TSHUT is still present during host read, then this bit will try to be cleared when host read but finally keep triggered because TSHUT still exists.

7.4 Device Functional Modes

7.4.1 Forward Mode

When input source is connected to VBUS, BQ25770G is in forward mode to regulate system and charge battery.

7.4.1.1 System Voltage Regulation with Narrow VDC Architecture

The device employs Narrow VDC architecture (NVDC) with BATFET separating the system from the battery. The minimum system voltage is set by VSYS MIN(). Even with a depleted battery, the system is regulated at VSYS MIN() setting. To prevent inrush current from input side, when there is an step up new value written into VSYS MIN(), the device can support soft positive slew rate DAC transition at 6.25mV/us, 3.125mV/us and 1.5625mV/us with corresponding configuration at EN_VSYS_MIN_SOFT_SR bits. The soft slew rate feature is not effective on step down direction . By default EN_VSYS_MIN_SOFT_SR=0b, there is no soft transition control for both step up and step down direction.

When the battery is below minimum system voltage setting, the BATFET operates in linear mode (LDO mode), and the system is regulated at VSYS MIN register value. As the battery voltage rises above the minimum system voltage, BATFET is fully on. When in charging or in supplement mode, the voltage difference between the system and battery is the V_{DS} of the BATFET. System voltage is regulated 150 mV above battery voltage when BATFET is turned off (no charging or no supplement current).

7.4.1.2 Battery Charging

The BQ25770G charges cell battery in trickle charge, pre-charge, constant current (CC), and constant voltage (CV) mode. Based on CELL_BATPREZ pin setting, the charger sets default battery voltage 4.2V/cell to CHARGE_VOLTAGE(). According to battery capacity, the host programs appropriate charge current to CHARGE_CURRENT() register. When battery is full or battery is not in good condition to charge, host terminates charge by setting CHRG_INHIBIT bit to 1b, or setting CHARGE_CURRENT() to zero.

7.4.2 USB On-The-Go Mode

The BQ25770G supports USB OTG functionality to deliver power from the battery to other portable devices through USB port (reverse mode). The OTG output voltage is compliant with USB PD specification, including 5 V~28V. The output current regulation is compliant with USB Type-C and PD specification, including 500 mA, 1.5 A, 3 A and 5 A etc.

Similar to forward operation, the device switches from PWM operation to PFM operation at light load to improve efficiency.

7.4.3 Pass Through Mode (PTM)-Patented Technology

The charger can be operated in the pass through mode (PTM) to improve efficiency. In PTM, the Buck and Boost high-side FETs (Q1 and Q4) are both turned on, while the Buck and Boost low-side FETs are both turned off. The input power is directly passed through the charger to the system. The switching losses of MOSFETs and the inductor core loss are saved. The charger quiescent current under PTM mode is also minimized (around 2.5 mA) to increase light load efficiency.

When programmable power supply (PPS) is used as input adapter, PTM mode can also be leveraged to achieve battery flash charge under battery fast charge period. By enabling flash charge, the charge efficiency can be further improved with even higher charging current. During pre-charge and termination period the charger can go back to buck-boost mode.

The charger can exit PTM to buck-boost operation and automatically return to PTM under certain protection scenarios (TI patent).

To prevent reverse boost back after adapter removal when charger is in PTM operation before removal. There is light load PTM auto exit feature which can be enabled by configuring PTM_EXIT_LIGHT_LOAD=1b.

Charger will be transition from normal Buck-Boost operation to PTM operation by setting EN_PTM = 1b; and will transition out of PTM mode with host control by setting EN_PTM =0b.

7.4.4 Learn Mode

When both VBUS and VBAT exist, setting EN_LEARN=1b to enable mode to allow device to shut off converter and discharge battery to support the system. In this way it can calibrates the battery gas gauge over a complete discharge/charge cycle. When the battery voltage is below battery depletion threshold, the EC host will set EN_LEARN bit back to 0b to switch the device back in forward mode. When device is under learn mode if CELL_BATPRES pin is pulled lower than V_{CELL} BATPRES FALL for 1ms deglitch time, then device exits LEARN mode and reset EN_LEARN bit is set back to 0 automatically.

7.5 Programming

The charger supports battery-charger commands that use either Write-Word or Read-Word protocols, as summarized in [Section 7.5.1.1](#page-52-0). The SMBus address is 7 bits 09h (0001001b), for 8 bits SMBus commands the last bit is read(1b)/write(0b) bit. Therefore 8 bits SMBus address command is integrated as 0b0001001 X (0x12H for write/0x13H for read).. The ManufacturerID and DeviceID registers are assigned to identify the charger device. The ManufacturerID register command always returns 40h.

7.5.1 SMBus Interface

The device operates as a target, receives control inputs from the embedded controller host through the SMBus interface. The device uses a simplified subset of the commands documented in *System Management Bus Specification V1.1*, which can be downloaded from [www.smbus.org.](http://www.smbus.org) The device uses the SMBus read-word and write-word protocols (shown in [Table 7-10](#page-52-0) and [Table 7-11\)](#page-52-0) to communicate with the smart battery. The device performs only as a SMBus target device with address 0b0001001 X (0x12H for write/0x13H for read) and does not initiate communication on the bus. In addition, the device has two identification registers, a 16-bit device ID register (0xFFH) and a 16-bit manufacturer ID register (0xFEH).

SMBus communication starts when VBUS is above $V_{VBUS-UVLO}$ or VBAT is above $V_{VBAT-UVLO}$.

The data (SDA) and clock (SCL) pins have Schmitt-trigger inputs that can accommodate slow edges. Choose pullup resistors (10 kΩ) for SDA and SCL to achieve rise times according to the SMBus specifications. Communication starts when the host signals a start condition, which is a high-to-low transition on SDA, while SCL is high. When the host has finished communicating, the host issues a stop condition, which is a low-to-high transition on SDA, while SCL is high. The bus is then free for another transmission. When timeout condition is met, for example start condition is active for more than 35ms and there is no stop condition triggered, then charger SMbus communication will automatically reset and communication lines are free for another transmission. [Figure 7-12](#page-52-0) and [Figure 7-13](#page-53-0) show the timing diagram for signals on the SMBus interface. The address byte, command byte, and data bytes are transmitted between the start and stop conditions. The SDA

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state changes only while SCL is low, except for the start and stop conditions. Data is transmitted in 8-bit bytes and is sampled on the rising edge of SCL. Nine clock cycles are required to transfer each byte in or out of the device because either the host or the target acknowledges the receipt of the correct byte during the ninth clock cycle. The BQ25770G supports the charger commands listed in [Table 7-10](#page-52-0).

7.5.1.1 SMBus Write-Word and Read-Word Protocols

Table 7-10. Write-Word Format

ls (1) (2)	Target ADDRESS⁽¹⁾	W (1) (3)	ACK (4) (5)	COMMAND $BYTE^{(1)}$	ACK (4) (5)	LOW DATA $BYTE^{(1)}$	ACK (4)(5)	HIGH DATA $ $ BYTE (1)	ACK (4) (5)	l P (1)(6)
	^ㄱ bits	1 _h	1b	8 bits	1 _b	8 bits	1 _b	8 bits	1 _b	
	MSB LSB			MSB LSB		MSB LSB		MSB LSB		

(1) Controller to target

 (2) S = Start condition or repeated start condition

(3) W = Write bit (logic-low)

(4) Target to controller (shaded gray)

(5) ACK = Acknowledge (logic-low)

 (6) P = Stop condition

Table 7-11. Read-Word Format

(1) Controller to target

(2) S = Start condition or repeated start condition

(3) W = Write bit (logic-low)

(4) Target to controller (shaded gray)

(5) ACK = Acknowledge (logic-low)

 (6) R = Read bit (logic-high)

 (7) NACK = Not acknowledge (logic-high)

 (8) P = Stop condition

7.5.1.2 Timing Diagrams

Figure 7-12. SMBus Write Timing

F = ACKNOWLEDGE bit clocked into controller

Figure 7-13. SMBus Read Timing

EXAS

7.6 BQ25770G Registers

Table 7-12 lists the memory-mapped registers for the BQ25770G registers. All register offset addresses not listed in Table 7-12 should be considered as reserved locations and the register contents should not be modified.

Table 7-12. BQ25770G Registers

Complex bit access types are encoded to fit into small table cells. Table 7-13 shows the codes that are used for access types in this section.

Table 7-13. BQ25770G Access Type Codes

7.6.1 REG0x12_ChargeOption0 Register (Address = 12h) [Reset = E70Eh]

REG0x12_ChargeOption0 is shown in Figure 7-14 and described in Table 7-14.

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Figure 7-14. REG0x12_ChargeOption0 Register

Table 7-14. REG0x12_ChargeOption0 Register Field Descriptions

7.6.2 REG0x14_CHARGE_CURRENT Register (Address = 14h) [Reset = 0000h]

REG0x14_CHARGE_CURRENT is shown in Figure 7-15 and described in Table 7-15.

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Figure 7-15. REG0x14_CHARGE_CURRENT Register

Table 7-15. REG0x14_CHARGE_CURRENT Register Field Descriptions

7.6.3 REG0x15_CHARGE_VOLTAGE Register (Address = 15h) [Reset = 0000h]

REG0x15_CHARGE_VOLTAGE is shown in Figure 7-16 and described in Table 7-16.

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Figure 7-16. REG0x15_CHARGE_VOLTAGE Register

Table 7-16. REG0x15_CHARGE_VOLTAGE Register Field Descriptions

7.6.4 REG0x17_ChargeProfile Register (Address = 17h) [Reset = 3020h]

REG0x17_ChargeProfile is shown in Figure 7-17 and described in Table 7-17.

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Table 7-17. REG0x17_ChargeProfile Register Field Descriptions

7.6.5 REG0x18_GateDrive Register (Address = 18h) [Reset = 246Ch]

REG0x18_GateDrive is shown in Figure 7-18 and described in Table 7-18.

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Figure 7-18. REG0x18_GateDrive Register

Table 7-18. REG0x18_GateDrive Register Field Descriptions

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Table 7-18. REG0x18_GateDrive Register Field Descriptions (continued)

7.6.6 REG0x19_ChargeOption5 Register (Address = 19h) [Reset = 0685h]

REG0x19_ChargeOption5 is shown in Figure 7-19 and described in Table 7-19.

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Figure 7-19. REG0x19_ChargeOption5 Register

Table 7-19. REG0x19_ChargeOption5 Register Field Descriptions

Table 7-19. REG0x19_ChargeOption5 Register Field Descriptions (continued)

7.6.7 REG0x1A_AutoCharge Register (Address = 1Ah) [Reset = 01C2h]

REG0x1A_AutoCharge is shown in Figure 7-20 and described in Table 7-20.

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Figure 7-20. REG0x1A_AutoCharge Register

Table 7-20. REG0x1A_AutoCharge Register Field Descriptions

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Table 7-20. REG0x1A_AutoCharge Register Field Descriptions (continued)

7.6.8 REG0x1B_ChargerStatus0 Register (Address = 1Bh) [Reset = 0000h]

REG0x1B_ChargerStatus0 is shown in Figure 7-21 and described in Table 7-21.

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ChargeStatus0()

Figure 7-21. REG0x1B_ChargerStatus0 Register

Table 7-21. REG0x1B_ChargerStatus0 Register Field Descriptions

Table 7-21. REG0x1B_ChargerStatus0 Register Field Descriptions (continued)

7.6.9 REG0x20_ChargerStatus1 Register (Address = 20h) [Reset = 0000h]

REG0x20_ChargerStatus1 is shown in Figure 7-22 and described in Table 7-22.

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Figure 7-22. REG0x20_ChargerStatus1 Register

Table 7-22. REG0x20_ChargerStatus1 Register Field Descriptions

Table 7-22. REG0x20_ChargerStatus1 Register Field Descriptions (continued)

Table 7-22. REG0x20_ChargerStatus1 Register Field Descriptions (continued)

7.6.10 REG0x21_Prochot_Status_Register (Address = 21h) [Reset = 3800h]

REG0x21_Prochot_Status_Register is shown in Figure 7-23 and described in Table 7-23.

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Figure 7-23. REG0x21_Prochot_Status_Register

Table 7-23. REG0x21_Prochot_Status_Register Field Descriptions

Table 7-23. REG0x21_Prochot_Status_Register Field Descriptions (continued)

7.6.11 REG0x22_IIN_DPM Register (Address = 22h) [Reset = 0320h]

REG0x22_IIN_DPM is shown in Figure 7-24 and described in Table 7-24.

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Figure 7-24. REG0x22_IIN_DPM Register

Table 7-24. REG0x22_IIN_DPM Register Field Descriptions

7.6.12 REG0x23_ADC_VBUS Register (Address = 23h) [Reset = 0000h]

REG0x23_ADC_VBUS is shown in Figure 7-25 and described in Table 7-25.

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Figure 7-25. REG0x23_ADC_VBUS Register

Table 7-25. REG0x23_ADC_VBUS Register Field Descriptions

7.6.13 REG0x24_ADC_IBAT Register (Address = 24h) [Reset = 0000h]

REG0x24_ADC_IBAT is shown in Figure 7-26 and described in Table 7-26.

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Figure 7-26. REG0x24_ADC_IBAT Register

Table 7-26. REG0x24_ADC_IBAT Register Field Descriptions

7.6.14 REG0x25_ADC_IIN Register (Address = 25h) [Reset = 0000h]

REG0x25_ADC_IIN is shown in Figure 7-27 and described in Table 7-27.

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Figure 7-27. REG0x25_ADC_IIN Register

Table 7-27. REG0x25_ADC_IIN Register Field Descriptions

7.6.15 REG0x26_ADC_VSYS Register (Address = 26h) [Reset = 0000h]

REG0x26_ADC_VSYS is shown in Figure 7-28 and described in Table 7-28.

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Figure 7-28. REG0x26_ADC_VSYS Register

Table 7-28. REG0x26_ADC_VSYS Register Field Descriptions

7.6.16 REG0x27_ADC_VBAT Register (Address = 27h) [Reset = 0000h]

REG0x27_ADC_VBAT is shown in Figure 7-29 and described in Table 7-29.

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Figure 7-29. REG0x27_ADC_VBAT Register

Table 7-29. REG0x27_ADC_VBAT Register Field Descriptions

7.6.17 REG0x28_ADC_PSYS Register (Address = 28h) [Reset = 0000h]

REG0x28_ADC_PSYS is shown in Figure 7-30 and described in Table 7-30.

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Figure 7-30. REG0x28_ADC_PSYS Register

Table 7-30. REG0x28_ADC_PSYS Register Field Descriptions

7.6.18 REG0x29_ADC_CMPIN_TR Register (Address = 29h) [Reset = 0000h]

REG0x29_ADC_CMPIN_TR is shown in Figure 7-31 and described in Table 7-31.

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Figure 7-31. REG0x29_ADC_CMPIN_TR Register

Table 7-31. REG0x29_ADC_CMPIN_TR Register Field Descriptions

7.6.19 REG0x30_ChargeOption1 Register (Address = 30h) [Reset = 3201h]

REG0x30_ChargeOption1 is shown in Figure 7-32 and described in Table 7-32.

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Figure 7-32. REG0x30_ChargeOption1 Register 15 14 13 12 11 10 9 8 EN_IBAT | EN_LWPWR_C MP PSYS_CONFIG | RSNS_RAC | RSNS_RSR | PSYS_RATIO | EN_OTG_BIG_ CAP R/W-0h R/W-0h R/W-3h R/W-0h R/W-0h R/W-1h R/W-0h 7 6 5 4 3 2 1 0 SYSOVP_MAX CMP_POL CMP_DEG FRC_CONV_O FF EN_PTM EN_SHIP_DCH G EN_SC_VBUS ACP R/W-0h R/W-0h R/W-0h R/W-0h R/W-0h R/W-0h R/W-1h

Table 7-32. REG0x30_ChargeOption1 Register Field Descriptions

Table 7-32. REG0x30_ChargeOption1 Register Field Descriptions (continued)

Table 7-32. REG0x30_ChargeOption1 Register Field Descriptions (continued)

7.6.20 REG0x31_ChargeOption2 Register (Address = 31h) [Reset = 00B7h]

REG0x31_ChargeOption2 is shown in Figure 7-33 and described in Table 7-33.

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Figure 7-33. REG0x31_ChargeOption2 Register

Table 7-33. REG0x31_ChargeOption2 Register Field Descriptions

Table 7-33. REG0x31_ChargeOption2 Register Field Descriptions (continued)

7.6.21 REG0x32_ChargeOption3 Register (Address = 32h) [Reset = 0534h]

REG0x32_ChargeOption3 is shown in Figure 7-34 and described in Table 7-34.

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Figure 7-34. REG0x32_ChargeOption3 Register

Table 7-34. REG0x32_ChargeOption3 Register Field Descriptions

Table 7-34. REG0x32_ChargeOption3 Register Field Descriptions (continued)

7.6.22 REG0x33_ProchotOption0_Register (Address = 33h) [Reset = 4A39h]

REG0x33_ProchotOption0_Register is shown in Figure 7-35 and described in Table 7-35.

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Figure 7-35. REG0x33_ProchotOption0_Register

Table 7-35. REG0x33_ProchotOption0_Register Field Descriptions

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Table 7-35. REG0x33_ProchotOption0_Register Field Descriptions (continued)

7.6.23 REG0x34_ProchotOption1 Register (Address = 34h) [Reset = 41A0h]

REG0x34_ProchotOption1 is shown in Figure 7-36 and described in Table 7-36.

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Figure 7-36. REG0x34_ProchotOption1 Register

Table 7-36. REG0x34_ProchotOption1 Register Field Descriptions

Table 7-36. REG0x34_ProchotOption1 Register Field Descriptions (continued)

7.6.24 REG0x35_ADCOption Register (Address = 35h) [Reset = 9000h]

REG0x35_ADCOption is shown in Figure 7-37 and described in Table 7-37.

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Table 7-37. REG0x35_ADCOption Register Field Descriptions

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Table 7-37. REG0x35_ADCOption Register Field Descriptions (continued)

7.6.25 REG0x36_ChargeOption4 Register (Address = 36h) [Reset = 0048h]

REG0x36_ChargeOption4 is shown in Figure 7-38 and described in Table 7-38.

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Table 7-38. REG0x36_ChargeOption4 Register Field Descriptions

Table 7-38. REG0x36_ChargeOption4 Register Field Descriptions (continued)

7.6.26 REG0x37_Vmin_Active_Protection Register (Address = 37h) [Reset = 0024h]

REG0x37_Vmin_Active_Protection is shown in Figure 7-39 and described in Table 7-39.

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Figure 7-39. REG0x37_Vmin_Active_Protection Register

Table 7-39. REG0x37_Vmin_Active_Protection Register Field Descriptions

7.6.27 REG0x3B_OTG_VOLTAGE Register (Address = 3Bh) [Reset = 03E8h]

REG0x3B_OTG_VOLTAGE is shown in Figure 7-40 and described in Table 7-40.

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Figure 7-40. REG0x3B_OTG_VOLTAGE Register 15 14 13 12 11 10 9 8 RESERVED **DESERVED OTG_VOLTAGE** R-0h R/W-FAh 7 6 5 4 3 2 1 0 OTG VOLTAGE RESERVED R/W-FAh R-0h

Table 7-40. REG0x3B_OTG_VOLTAGE Register Field Descriptions

7.6.28 REG0x3C_OTG_CURRENT Register (Address = 3Ch) [Reset = 01E0h]

REG0x3C_OTG_CURRENT is shown in Figure 7-41 and described in Table 7-41.

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Figure 7-41. REG0x3C_OTG_CURRENT Register

Table 7-41. REG0x3C_OTG_CURRENT Register Field Descriptions

7.6.29 REG0x3D_VINDPM Register (Address = 3Dh) [Reset = 0280h]

REG0x3D_VINDPM is shown in Figure 7-42 and described in Table 7-42.

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Table 7-42. REG0x3D_VINDPM Register Field Descriptions

7.6.30 REG0x3E_VSYS_MIN Register (Address = 3Eh) [Reset = 0528h]

REG0x3E_VSYS_MIN is shown in Figure 7-43 and described in Table 7-43.

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Table 7-43. REG0x3E_VSYS_MIN Register Field Descriptions

7.6.31 REG0x3F_IIN_HOST Register (Address = 3Fh) [Reset = 0320h]

REG0x3F_IIN_HOST is shown in Figure 7-44 and described in Table 7-44.

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Figure 7-44. REG0x3F_IIN_HOST Register

Table 7-44. REG0x3F_IIN_HOST Register Field Descriptions

7.6.32 REG0x60_AUTOTUNE_READ Register (Address = 60h) [Reset = 0000h]

REG0x60_AUTOTUNE_READ is shown in Figure 7-45 and described in Table 7-45.

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Figure 7-45. REG0x60_AUTOTUNE_READ Register

Table 7-45. REG0x60_AUTOTUNE_READ Register Field Descriptions

7.6.33 REG0x61_AUTOTUNE_FORCE Register (Address = 61h) [Reset = A8A8h]

REG0x61_AUTOTUNE_FORCE is shown in Figure 7-46 and described in Table 7-46.

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Figure 7-46. REG0x61_AUTOTUNE_FORCE Register

Table 7-46. REG0x61_AUTOTUNE_FORCE Register Field Descriptions

7.6.34 REG0x62_GM_ADJUST_FORCE Register (Address = 62h) [Reset = 00C7h]

REG0x62_GM_ADJUST_FORCE is shown in Figure 7-47 and described in Table 7-47.

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Figure 7-47. REG0x62_GM_ADJUST_FORCE Register

Table 7-47. REG0x62_GM_ADJUST_FORCE Register Field Descriptions

Table 7-47. REG0x62_GM_ADJUST_FORCE Register Field Descriptions (continued)

7.6.35 REG0xFD_VIRTUAL_CONTROL Register (Address = FDh) [Reset = 0013h]

REG0xFD_VIRTUAL_CONTROL is shown in Figure 7-48 and described in Table 7-48.

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Figure 7-48. REG0xFD_VIRTUAL_CONTROL Register

Table 7-48. REG0xFD_VIRTUAL_CONTROL Register Field Descriptions

Table 7-48. REG0xFD_VIRTUAL_CONTROL Register Field Descriptions (continued)

7.6.36 REG0xFE_Manufacture_ID Register (Address = FEh) [Reset = 0040h]

REG0xFE_Manufacture_ID is shown in Figure 7-49 and described in Table 7-49.

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Figure 7-49. REG0xFE_Manufacture_ID Register

Table 7-49. REG0xFE_Manufacture_ID Register Field Descriptions

7.6.37 REG0xFF_Device_ID Register (Address = FFh) [Reset = 000Ah]

REG0xFF_Device_ID is shown in Figure 7-50 and described in Table 7-50.

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Figure 7-50. REG0xFF_Device_ID Register

Table 7-50. REG0xFF_Device_ID Register Field Descriptions

8 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

8.1 Application Information

The BQ25770EVM evaluation module (EVM) is a complete charger module for evaluating the BQ25770G. The application curves were taken using the BQ25770EVM.

8.2 Typical Application

Figure 8-1. Application Diagram of BQ25770G

8.2.1 Design Requirements

(1) Refer to battery specification for settings.

(2) Refer to adapter specification for settings for Input Voltage and Input Current Limit.

8.2.2 Detailed Design Procedure

The parameters are configurable using the evaluation software. The simplified application circuit (see [Figure](#page-112-0) [8-1](#page-112-0), as the application diagram) shows the minimum component requirements. Inductor, capacitor, and MOSFET selection are explained in the rest of this section. Refer to the EVM user's guide for the complete application schematic.

8.2.2.1 ACP-ACN Input Filter

The BQ25770G input current sensing through ACP_A-ACN_A and ACP_B-ACN_B are critical to ensure IINDPM/IOTG regulation stability. Parasitic inductance on board will generate high frequency ringing on ACP_A-ACN A and ACP_B-ACN_B which overwhelms converter sensed inductor current information. Larger parasitic inductance will generate larger sense current ringing which could cause the average current control loop to go into oscillation. Therefore ACP_A-ACN_A and ACP_B-ACN_B sensing information need to be conditioned.

For real system board condition, we suggest using below circuit design to get best result and filter noise induced from different PCB parasitic factor. The filter is effective and the delay of on the sensed signal is small, therefore there is no concern for average current mode control. On ACN_A and ACN_B side the maximum capacitance is 1*10-μF MLCC shown below, the 10 nF + 1 nF EMI filtering capacitance can be neglected comparing to the 10-μF MLCC. When the 10-μF MLCC is used on ACN_A and ACN_B, then differential 100-nF ~ 220-nF filter capacitors are recommended for ACP_A-ACN_A and ACP_B-ACN_B to prevent pulse reverse current through RAC.

Figure 8-2. ACN-ACP Input Filter

8.2.2.2 Inductor Selection

The BQ25770G has two selectable fixed switching frequency 600 kHz/800 kHz. Higher switching frequency allows the use of smaller inductance. Inductor saturation current should be higher than the charging current (I_{CHG}) plus half the ripple current (I_{RIPPLE}) :

$$
I_{\text{SAT}} \geq I_{\text{CHG}} + (1/2) I_{\text{RIPPLE}}
$$

(3)

The inductor ripple current in buck operation depends on input voltage (V_{IN}), duty cycle (D_{BUCK} = V_{OUT}/V_{IN}), switching frequency (f_S) and inductance (L):

 $I_{RIPPLE~BUCK} = V_{IN} \times D_{BUCK} \times (1-D_{BUCK}) / (f_S \times L)$ (4)

During boost operation, the duty cycle is:

 $D_{\text{ROOST}} = 1 - (V_{\text{IN}}/V_{\text{BAT}})$

and the ripple current is:

 I_{RIPPLE} BOOST = (V_{IN} × D_{BOOST}) / (f_S × L)

The maximum inductor ripple current happens with $D = 0.5$ or close to 0.5. For example, the battery charging voltage range is from 12 V to 16.8 V for 4-cell battery pack. For 28-V adapter voltage, 14-V battery voltage gives the maximum inductor ripple current.

The recommended inductor DCR range is 5 m $\Omega \sim 25$ m Ω for each phase. Inductor DCR beyond this range may hold system stability risk which is not recommended. Upon different switching frequency and VBUS input voltage recommended inductance are summarized in Table 8-1. Inductance lower than the recommendation could result in large inductor ripple and high inductor core loss which is not preferred.

	$VBUS = 20 V$	$VBUS = 28 V$	$VBUS = 36 V$	
Fsw=600 kHz	$2.2 \mu H$	$2.2 \mu H$	$3.3 \mu H$	
Fsw=800 kHz	1.5 µH	1.5 µH	$2.2 \mu H$	

Table 8-1. Inductance Selection Recommendation

8.2.2.3 Input Capacitor

Input capacitor should have enough ripple current rating to absorb input switching ripple current. The worst case RMS ripple current is half of the charging current (plus system current there is any system load) when duty cycle is 0.5 in buck mode. If the converter does not operate at 50% duty cycle, then the worst case capacitor RMS current occurs where the duty cycle is closest to 50% and can be estimated by Equation 5:

$$
I_{CIN} = I_{CHG} \times \sqrt{D \times (1 - D)}
$$

Low ESR ceramic capacitor such as X7R or X5R is preferred for input decoupling capacitor and should be placed in front of RAC current sensing and as close as possible to the power stage half bridge MOSFETs. Capacitance after RAC before power stage half bridge should be limited to10µF+10nF+1nF referring to [Figure](#page-113-0) [8-2](#page-113-0) diagram. Voltage rating of the capacitor must be higher than normal input voltage level, 35 V rating or higher capacitor is preferred for 28 V input voltage. Minimum 10 pieces of 10-µF 0603 size capacitors are suggested for 28V/140 W adapter design. 50-V rating or higher capacitor is preferred for 36-V input voltage. Minimum 10*10μF 0805 capacitors are needed when power reaches 36 V/180 W. Under different input voltage the minimum input capacitance requirement is summarized in Table 8-2, [Table 8-3](#page-115-0) and [Table 8-4.](#page-115-0) For quasi dual phase it is recommended to spread the MLCC caps before RAC_A and RAC_B. 1*10nF+1nF 0402 package MLCC capacitors (EMI filter purpose) are recommended to be placed as close as possible to both phase A and phase B half bridge MOSFETs.

Ceramic capacitors show a dc-bias effect. This effect reduces the effective capacitance when a dc-bias voltage is applied across a ceramic capacitor, as on the input capacitor of a charger. The effect may lead to a significant capacitance drop, especially for high input voltages and small capacitor packages. See the manufacturer's data sheet about the derating performance with a dc bias voltage applied. It may be necessary to choose a higher voltage rating or nominal capacitance value in order to get the required capacitance value at the operating point. Tantalum capacitors (POSCAP) can avoid dc-bias effect and temperature variation effect which is recommended especially for 28-V and 36-V higher power application.

Table 8-2. Input Capacitance Requirement for 20-V/100-W System

(5)

Table 8-3. Input Capacitance Requirement for 28-V/140-W System

8.2.2.4 Output Capacitor

Output capacitor also should have enough ripple current rating to absorb output switching ripple current. The preferred ceramic capacitor is 35-V X7R or X5R for output capacitor. Minimum 7 pieces of 10-µF 0603 size capacitor is suggested to be placed as close as possible to Q3&Q4 half bridge (between Q4 drain and Q3 source terminal), when the power reaches 140 W/180 W 2 more 0603 MLCC are recommended at system output. Recommend to place minimum 2*10 µF after the charge current sense resistor for best stability. The overall minimum VSYS effective capacitance should be 50 μF including all the capacitance distributed along the VSYS output line like input capacitance on the next stage VRs referring to Table 8-5.

Ceramic capacitors show a dc-bias effect. This effect reduces the effective capacitance when a dc-bias voltage is applied across a ceramic capacitor, as on the output capacitor of a charger. The effect may lead to a significant capacitance drop, especially for high output voltages and small capacitor packages. See the manufacturer's data sheet about the derating performance with a dc bias voltage applied. It may be necessary to choose a higher voltage rating or nominal capacitance value in order to get the required capacitance value at the operating point.

OUTPUT CAPACITORS VS TOTAL INPUT POWER	100 W	140 W	180 W
Minimum Effective Output Capacitance	50 uF	50 uF	50 uF
Minimum output capacitors at charger VSYS output terminal	7*10 µF (0603 35 V MLCC)	9*10 µF (0603 35 V MLCC)	$ 9*10 \mu F (0603 35 V MLCC) $ for VBUS<=28 V 9*10 µF (0805 50 V MLCC) for VBUS=36 V

Table 8-5. Minimum Output Capacitance Requirement

Table 8-5. Minimum Output Capacitance Requirement (continued)

It is common under higher system power the total next stage (Vcore) input capacitance could be increased accordingly. These capacitance are also counted as charger system output capacitance. When these capacitance is too large it could also influence controller stability and maximum effective output capacitance are listed below for reference.

8.2.2.5 Power MOSFETs Selection

Six external N-channel MOSFETs are used for a synchronous switching battery charger. The gate drivers are integrated into the IC with 5 V of gate drive voltage. MOSFET breakdown voltage (BV $_{DSS}$) rating refers to Table 8-7 based on different input voltage and application position. 5mm*6mm package MOSFET is preferred for better thermal performance and 3.3mm*3.3mm package MOSFET is preferred for higher power density design.

Table 8-7. MOSFET Voltage Rating Recommendation

Figure-of-merit (FOM) is usually used for selecting proper MOSFET based on a tradeoff between the conduction loss and switching loss. For the top side MOSFET, FOM is defined as the product of a MOSFET's on-resistance, $R_{DS(ON)}$, and the gate-to-drain charge, Q_{GD} . For the bottom side MOSFET, FOM is defined as the product of the MOSFET's on-resistance, $R_{DS(ON)}$, and the total gate charge, Q_G .

$$
FOM_{top} = R_{DS(on)} \cdot Q_{GD};\; FOM_{bottom} = R_{DS(on)} \cdot Q_G\tag{6}
$$

The lower the FOM value, the lower the total power loss. Usually lower $R_{DS(ON)}$ has higher cost with the same package size.

The top-side MOSFET loss includes conduction loss and switching loss. Taking buck mode operation as an example the power loss is a function of duty cycle $(D=V_{OUT}/V_{IN})$, charging current (I_{CHG}), MOSFET's onresistance (R_{DS(ON)}, top), input voltage (V_{IN}), switching frequency (f_S), turn-on time (t_{on}) and turn-off time (t_{off}):

$$
P_{top} = P_{con_top} + P_{sw_top}
$$
 (7)

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RIIMENTS

 I_L _{DC} is the average inductor DC current under buck mode; I_{ripple} is the inductor current ripple peak-to-peak value;

$$
P_{sw_top} = P_{IV_top} + P_{Qoss_top} + P_{Gate_top};
$$
\n
$$
(10)
$$

The first item $P_{\text{con top}}$ represents the conduction loss which is straight forward. The second term $P_{\text{sw top}}$ represents the multiple switching loss items in top MOSFET including voltage and current overlap losses (P_{IV top}), MOSFET parasitic output capacitance loss (P_{Qoss top}) and gate drive loss (P_{Gate top}). To calculate voltage and current overlap losses (P_{IV-top}) :

$$
P_{IV_top} = 0.5x V_{IN} \cdot I_{valley} \cdot t_{on} \cdot f_S + 0.5x V_{IN} \cdot I_{peak} \cdot t_{off} \cdot f_S
$$
\n(11)

$$
I_{\text{valley}} = I_{L_DC} - 0.5 \cdot I_{\text{ripple}} \text{ (inductor current valley value)};
$$
\n
$$
(12)
$$

 $I_{\text{peak}} = I_{\text{L DC}} + 0.5 \cdot I_{\text{ripole}}$ (inductor current peak value); (13)

- t_{on} is the MOSFET turn-on time that V_{DS} falling time from V_{IN} to almost zero (MOSFET turn on conduction voltage);
- $\rm t_{off}$ is the MOSFET turn-off time that I_{DS} falling time from I $\rm _{peak}$ to zero;

The MOSFET turn-on and turn-off times are given by:

$$
t_{on} = \frac{Q_{SW}}{I_{on}}, \quad t_{off} = \frac{Q_{SW}}{I_{off}}
$$
 (14)

where Q_{sw} is the switching charge, I_{on} is the turn-on gate driving current, and I_{off} is the turn-off gate driving current. If the switching charge is not given in MOSFET datasheet, it can be estimated by gate-to-drain charge (Q_{GD}) and gate-to-source charge (Q_{GS}) :

$$
Q_{sw} = Q_{GD} + Q_{GS} \tag{15}
$$

Gate driving current can be estimated by REGN voltage (V_{REGN}), MOSFET plateau voltage (V_{plt}), total turn-on gate resistance (R_{on}) , and turn-off gate resistance (R_{off}) of the gate driver:

$$
I_{on} = \frac{V_{REGN} - V_{plt}}{R_{on}}, I_{off} = \frac{V_{plt}}{R_{off}}
$$
 (16)

To calculate top MOSFET parasitic output capacitance loss $(P_{\text{Qoss top}})$:

 $P_{\text{Qoss top}} = 0.5 \cdot V_{\text{IN}} \cdot Q_{\text{oss}} \cdot f_{\text{S}}$ (17)

 Q_{oss} is the MOSFET parasitic output charge which can be found in MOSFET data sheet;

To calculate top MOSFET gate drive loss $(P_{\text{Gate_top}})$:

$$
P_{\text{Gate_top}} = V_{\text{IN}} \cdot Q_{\text{Gate_top}} \cdot f_{\text{S}}
$$
 (18)

- $\mathsf{Q}_{\mathsf{Gate_top}}$ is the top MOSFET gate charge which can be found in MOSFET data sheet;
- Note here V_{IN} is used instead of real gate drive voltage 6 V because, the gate drive 6 V is generated based on LDO from V_{IN} under buck mode, the total gate drive related loss are all considered when V_{IN} is used for gate drive loss calculation .

The bottom-side MOSFET loss also includes conduction loss and switching loss:

The first item P_{con} bottom represents the conduction loss which is straight forward. The second term P_{sw} bottom represents the multiple switching loss items in bottom MOSFET including reverse recovery losses (P_{RR} bottom), Dead time body diode conduction loss (P_{Dead bottom}) and gate drive loss (P_{Gate bottom}). The detail calculation can be found below:

$$
P_{RR_bottom} = V_{IN} \cdot Q_{rr} \cdot f_S
$$
 (22)

• Q_{rr} is the bottom MOSFET reverse recovery charge which can be found in MOSFET data sheet;

$$
PDead_bottom=VF · Ivalley · fS · tdead_rise+VF · Ipeak · fS · tdead_fall
$$
\n(23)

- V_F is the body diode forward conduction voltage drop;
- t_{dead rise} is the SW rising edge deadtime between top and bottom MOSFETs which is around 20 ns;
- $t_{\text{dead fall}}$ is the SW falling edge deadtime between top and bottom MOSFETs which is around 20 ns;

P_{Gate bottom} can follow the same method as top MOSFET gate drive loss calculation approach refer to [Equation](#page-117-0) [18.](#page-117-0)

N-channel MOSFETs is used for battery charging BATFET. The gate drivers are internally integrated into the IC with 5V of gate drive voltage. 30 V or higher voltage rating MOSFETs are preferred , the Ciss of N-channel MOSFET should be chosen less than 6 nF.

8.2.3 Application Curves

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9 Power Supply Recommendations

The valid adapter range is from 3.5 V (V_{VBUS_CONVEN}) to 40 V with at least 500-mA current rating. When CHRG_OK goes HIGH, the system is powered from adapter through the charger. When adapter is removed, the system is connected to battery through BATFET. Typically the battery depletion threshold should be greater than the VSYS_MIN so that the battery capacity can be fully utilized for maximum battery run time.

10 Layout 10.1 Layout Guidelines

Proper layout of the components to minimize high frequency current path loop (see [Section 10.2](#page-124-0)) is important to prevent electrical and magnetic field radiation and high frequency resonant problems. Here is a PCB layout priority list for proper layout.

Table 10-1. PCB Layout Guidelines (continued)

10.2 Layout Example

10.2.1 Layout Example Reference Top View

Based on the above layout guidelines, the quasi dual phase buck-boost charger layout example top view is shown below including all the key power components. Also the top layer PCB is shown separately to illustrate top layer PCB routing, main power flow and key optimization parasitic loop1-3.

Figure 10-1. Quasi Dual Phase Buck-Boost Charger Layout Reference Example Top View

Figure 10-2. Quasi Dual Phase Buck-Boost Charger Top Layer PCB Overview

11 Device and Documentation Support

11.1 Device Support

11.1.1 Third-Party Products Disclaimer

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11.2 Documentation Support

11.2.1 Related Documentation

For related documentation see the following:

- *Semiconductor and IC Package Thermal Metrics* Application Report [SPRA953](https://www.ti.com/lit/pdf/SPRA953)
- *BQ2571x Evaluation Module* User's Guide [SLUUBT8](https://www.ti.com/lit/pdf/SLUUBT8)
- *QFN/SON PCB Attachment* Application Report [SLUA271](https://www.ti.com/lit/pdf/SLUA271)

11.3 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on [ti.com.](https://www.ti.com) Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

11.4 Support Resources

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11.6 Electrostatic Discharge Caution

This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

11.7 Glossary

[TI Glossary](https://www.ti.com/lit/pdf/SLYZ022) This glossary lists and explains terms, acronyms, and definitions.

12 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

PACKAGING INFORMATION

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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TEXAS

ISTRUMENTS

TAPE AND REEL INFORMATION

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

PACKAGE MATERIALS INFORMATION

www.ti.com 16-May-2024

PACKAGE OUTLINE

REE0036A WQFN - 0.8 mm max height

PLASTIC QUAD FLATPACK - NO LEAD

NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.

EXAMPLE BOARD LAYOUT

REE0036A WQFN - 0.8 mm max height

PLASTIC QUAD FLATPACK - NO LEAD

4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).

EXAMPLE STENCIL DESIGN

REE0036A WQFN - 0.8 mm max height

PLASTIC QUAD FLATPACK - NO LEAD

NOTES: (continued)

5. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

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